19-2512; Rev 4; 3/08

EVALUATION KIT



±15kV ESD-Protected Touch-Screen Controllers Include DAC and Keypad Controller

General Description

Features

The MAX1233/MAX1234 are complete PDA controllers in 5mm × 5mm, 28-pin QFN and TQFN packages. They feature a 12-bit analog-to-digital converter (ADC), low on-resistance switches for driving resistive touch screens, an internal +1.0V/+2.5V or external reference, ±2°C accurate, on-chip temperature sensor, direct +6V battery monitor, keypad controller, 8-bit digital-to-analog converter (DAC), and a synchronous serial interface. Each of the keypad controllers' eight row and column inputs can be reconfigured as general-purpose parallel I/O pins (GPIO). All analog inputs are fully ESD protected, eliminating the need for external TransZorb[™] devices.

The MAX1233/MAX1234 offer programmable resolution and sampling rates. Interrupts from the devices alert the host processor when data is ready, when the screen is touched, or a key press is detected. Softwareconfigurable scan control and internal timers give the user flexibility without burdening the host processor. These devices consume only 260µA at the maximum sampling rate of 50ksps. Supply current falls to below 50µA for sampling rates of 10ksps. The MAX1233/MAX1234 are guaranteed over the -40°C to +85°C temperature range.

Applications

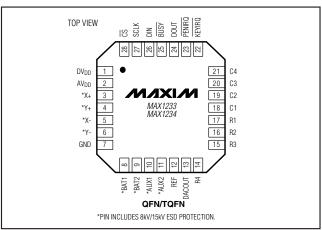
Personal Digital Assistants Pagers

Touch-Screen Monitors

Cellular Phones

- MP3 Players
- Portable Instruments
- Point-of-Sale Terminals

Pin Configuration



M/X/M

- ESD-Protected Analog Inputs ±15kV IEC 1000-4-2 Air-Gap Discharge ±8kV IEC 1000-4-2 Contact Discharge
- Single-Supply Operation +2.7V to +3.6V (MAX1233) +4.75V to +5.25V (MAX1234)
- ♦ 4-Wire Touch-Screen Interface
- Internal +1.0V/+2.5V Reference or External Reference (+1.0V to AV_{DD})
- ◆ SPI[™]/QSPI[™]/MICROWIRE[™]-Compatible 10MHz Serial Interface
- 12-Bit, 50ksps ADC Measures Resistive Touch-Screen Position and Pressure Two Auxiliary Analog Inputs Two Battery Voltages (0.5V to 6V) On-Chip Temperature
- ♦ 8-Bit DAC for LCD Bias Control
- ♦ 4 × 4 Keypad Programmable Controller Offers Up to Eight GPIO Pins
- Automatic Detection of Screen Touch, Key Press, and End of Conversion
- Programmable 8-, 10-, 12-Bit Resolution
- Programmable Conversion Rates
- ◆ AutoShutdown[™] Between Conversions
- Low Power
 - 260µA at 50ksps 50µA at 10ksps 6µA at 1ksps 0.3µA Shutdown Current
- ♦ 28-Pin 5mm × 5mm QFN and TQFN Packages

Ordering Information

PART	TEMP RANGE	PIN-PACKAGE
MAX1233EGI	-40°C to +85°C	28 QFN (5mm x 5mm)
MAX1233ETI	-40°C to +85°C	28 TQFN (5mm x 5mm)
MAX1234EGI	-40°C to +85°C	28 QFN (5mm x 5mm)
MAX1234ETI	-40°C to +85°C	28 TQFN (5mm x 5mm)

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MICROWIRE is a trademark of National Semiconductor Corp. AutoShutdown is a trademark of Maxim Integrated Products, Inc.

_ Maxim Integrated Products 1

For pricing, delivery, and ordering information, please contact Maxim Direct at 1-888-629-4642, or visit Maxim's website at www.maxim-ic.com.

ABSOLUTE MAXIMUM RATINGS

AV _{DD} to GND	-0.3V to +6V
DV _{DD} to AV _{DD}	-0.3V to +0.3V
Digital Inputs/Outputs to GND	0.3V to (DV _{DD} + 0.3V)
X+, Y+, X-, Y-, AUX1, AUX2,	
and REF to GND	0.3V to (AV _{DD} + 0.3V)
BAT1, BAT2 to GND	0.3V to +6V
Maximum ESD per IEC 1000-4-2	(per MIL STD-883 HBM)
X+, X-, Y+, Y-, AUX1, AUX2, B	AT1, BAT2±15kV

All Other Pins	.±2.5kV
Maximum Current into Any Pin	50mA
Continuous Power Dissipation ($T_A = +70^{\circ}C$)	
28-Pin QFN (derate 28.5mW/°C above +70°C)	2W
28-Pin TQFN (derate 28.5mW/°C above +70°C)	2W
Operating Temperature Range40°C to) +85°C
Storage Temperature Range60°C to	
Lead Temperature (soldering, 10s)	+300°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

 $(DV_{DD} = AV_{DD} = +2.7V \ to \ +3.6V \ (MAX1233), \ DV_{DD} = AV_{DD} = +4.75V \ to \ +5.25V \ (MAX1234), \ external \ reference \ V_{REF} = 2.5V \ (MAX1233), \ V_{REF} = 4.096V \ (MAX1234); \ f_{SCLK} = 10MHz, \ f_{SAMPLE} = 50ksps, \ 12-bit \ mode, \ 0.1\mu F \ capacitor \ at \ REF, \ T_A = -40^\circ C \ to \ +85^\circ C, \ unless \ otherwise \ noted. \ Typical \ values \ are \ at \ T_A = +25^\circ C.)$

PARAMETER	SYMBOL		CONDITIONS	MIN	TYP	MAX	UNITS				
		ANALOG-TO	D-DIGITAL CONVERTER								
DC ACCURACY (Note 1)											
Resolution		Software-p	rogrammable 8/10/12 bit			12	Bits				
No Missing Codes				11			Bits				
Deletive Accuracy (Note 2)	INL	12-bit mod	e		±0.8	±2	LSB				
Relative Accuracy (Note 2)		10-bit and	8-bit modes		±0.5		LSB				
Differential Neplinearity	DNL	12-bit mod	e		±0.8	±2	LSB				
Differential Nonlinearity	DINL	10-bit and	8-bit modes		±0.5		LOD				
Offset Error		12-bit mod	e		±0.5	±4	LSB				
Oliset Error		10-bit and	8-bit modes		±0.5		LSB				
		12-bit mod	e		±0.5	±4					
Gain Error (Note 3)		10-bit mod	е		±0.5		LSB				
		8-bit mode			±0.5						
Total Lipp diviste d Error	TUE	12-bit mod	e		±2		LSB				
Total Unadjusted Error	TUE	10-bit and	8-bit modes	±1			100				
Offset Temperature Coefficient					±0.4		ppm/°C				
Gain Temperature Coefficient					±0.4		ppm/°C				
Channel-to-Channel Offset					±0.1		LSB				
Channel-to-Channel Gain Matching					±0.1		LSB				
Noise		Including in	nternal V _{REF}		50		μV _{RMS}				
		Full-scale	MAX1233 AV _{DD} = DV _{DD} = +2.7V to +3.6V		±0.4						
Power-Supply Rejection	PSR	input	MAX1234 AV _{DD} = DV _{DD} = +5V ±5%	±0.3			— mV				
DYNAMIC SPECIFICATIONS (1) f _{SCLK} = 10MHz)	(Hz SINE WA)	/E, V _{IN} = 2.5	V _{P-P} FOR MAX1233, V _{IN} = 4.096V	P-P FOR	MAX123	4, 50ksps	,				
Signal-to-Noise Plus Distortion	SINAD				69		dB				

ELECTRICAL CHARACTERISTICS (continued)

 $(DV_{DD} = AV_{DD} = +2.7V \text{ to } +3.6V \text{ (MAX1233)}, DV_{DD} = AV_{DD} = +4.75V \text{ to } +5.25V \text{ (MAX1234)}, external reference V_{REF} = 2.5V \text{ (MAX1233)}, V_{REF} = 4.096V \text{ (MAX1234)}; f_{SCLK} = 10MHz, f_{SAMPLE} = 50ksps, 12-bit mode, 0.1\muF capacitor at REF, T_A = -40°C to +85°C, unless otherwise noted. Typical values are at T_A = +25°C.)$

PARAMETER	SYMBOL	CONDITIONS	MIN	ТҮР	MAX	UNITS
Total Harmonic Distortion	THD			-84		dB
Spurious-Free Dynamic Range	SFDR			84		dB
Full-Power Bandwidth		-3dB point		0.5		MHz
Full-Linear Bandwidth		SINAD > 67dB		50		kHz
CONVERSION RATE		·				
Internal Oscillator Frequency			8		11.5	MHz
Aperture Delay				30		ns
Aperture Jitter				<50		ps
Maximum Serial Clock Frequency	fsclk		10			MHz
Duty Cycle			30		70	%
AUXILIARY ANALOG INPUTS (A	UX1, AUX2)					1
Input Voltage Range			0		VREF	V
Input Leakage Current		Channel not selected or conversion stopped		±0.1	±1	μA
Input Capacitance				34		pF
BATTERY MONITOR INPUTS (BA	T1, BAT2)	1				
Input Voltage Range			0.5		6.0	V
		Sampling battery		10		kΩ
Input Impedance		Battery monitor OFF		1		GΩ
Accuracy		Internal reference	-3		+3	%
TEMPERATURE MEASUREMENT	ſ	•				
Temperature Range			-40		+85	°C
		Differential method (Note 4)		1.6		
Resolution		Single measurement method (Note 5)		0.3		°C
		Differential method (Note 4)		±3		
Accuracy		Single measurement method (Note 5)		±2		°C
INTERNAL ADC REFERENCE		• · · · · · · · · · · · · · · · · ·				
2 / 2 / 1 / 1		2.5V mode, T _A = +25°C	2.470	2.500	2.530	V
Reference Output Voltage	V _{REF}	1.0V mode, T _A = +25°C	0.980	1.000	1.020	
Output Tempco	TCVREF			60		ppm/°C
Reference Output Impedance		Normal operation		250		Ω
Reference Short-Circuit Current				18		mA
EXTERNAL ADC REFERENCE (II	NTERNAL RE	EFERENCE DISABLED, REFERENCE APPL	IED TO RE	F)		
Reference Input Voltage Range		(Note 6)	1.0		VDD	V
Input Impedance		$\overline{\text{CS}} = \text{GND or V}_{\text{DD}}$		1		GΩ
•		V _{REF} = +2.5V at 50ksps (MAX1233)		5	10	
		V _{REF} = +4.096V at 50ksps (MAX1234)	1	8	15	μA
Input Current		$V_{REF} = +4.090V at 30ksps (10AX1234)$		0	10	μΛ



ELECTRICAL CHARACTERISTICS (continued)

 $(DV_{DD} = AV_{DD} = +2.7V \text{ to } +3.6V \text{ (MAX1233)}, DV_{DD} = AV_{DD} = +4.75V \text{ to } +5.25V \text{ (MAX1234)}, external reference V_{REF} = 2.5V \text{ (MAX1233)}, V_{REF} = 4.096V \text{ (MAX1234)}; f_{SCLK} = 10MHz, f_{SAMPLE} = 50ksps, 12-bit mode, 0.1\muF capacitor at REF, T_A = -40°C to +85°C, unless otherwise noted. Typical values are at T_A = +25°C.)$

PARAMETER	SYMBOL	CONDITIONS	MIN	ТҮР	MAX	UNITS	
	•	DIGITAL-TO-ANALOG CONVERTER				•	
DC ACCURACY							
Resolution					8	Bits	
Integral Linearity Error	INL	(Note 7)			±1.0	LSB	
Differential Linearity Error	DNL	No missing codes			±1.0	LSB	
Offset Error	Vos	(Note 8)		±1	±25	mV	
Offset Error Temperature Coefficient				1		ppm/°C	
Full-Scale Error		Code = 255, no load			5	%	
Full-Scale Error Temperature Coefficient		Code = 255, no load		±10		ppm/°C	
DYNAMIC PERFORMANCE		·				•	
Voltage Output Slew Rate		Positive and negative		0.4		V/µs	
Output Settling Time		0.5LSB; 50k Ω and 50pF load (Note 9)		20		μs	
Glitch Impulse		Code 127 to 128		40		nV/s	
Wake-Up Time		From shutdown		50		μs	
DAC OUTPUT		·				•	
Internal DAC Reference	VREFDAC	(Note 10)	0.85 × AV _{DD}	0.9 × AV _{DD}	0.95 × AV _{DD}	V	
		Code = 255; 0 to 100µA		0.5		1.05	
Output Load Regulation		Code = 0; 0 to 100µA		LSB			
Output Resistance		Power-down mode		1.0		MΩ	
· · ·		TOUCH-SCREEN CONTROLLER					
		Y+, X+		7			
On-Resistance		Y-, X-		9		Ω	
Touch-Detection Internal Pullup Resistance		X+ to AV _{DD}		1		MΩ	
		KEYPAD CONTROLLER				•	
Pullup Resistance		C4, C3, C2, C1 (Note 11)		0.5		kΩ	
Pulldown Resistance		R4, R3, R2, R1 (Note 11)		16		kΩ	
		DIGITAL INTERFACE					
DIGITAL INPUTS (SCLK, CS, DI	N, R_, C_)						
Input Voltage Low	VIL				0.3 × DV _{DD}	V	
Input Voltage High	VIH		0.7 × DV _{DD}			V	
Input Leakage Current	١L			±0.1	±1	μA	

MAX1233/MAX1234

ELECTRICAL CHARACTERISTICS (continued)

 $(DV_{DD} = AV_{DD} = +2.7V \text{ to } +3.6V \text{ (MAX1233)}, DV_{DD} = AV_{DD} = +4.75V \text{ to } +5.25V \text{ (MAX1234)}, external reference V_{REF} = 2.5V \text{ (MAX1233)}, V_{REF} = 4.096V \text{ (MAX1234)}; f_{SCLK} = 10MHz, f_{SAMPLE} = 50ksps, 12-bit mode, 0.1\muF capacitor at REF, T_A = -40°C \text{ to } +85°C$, unless otherwise noted. Typical values are at T_A = +25°C.)

PARAMETER	SYMBOL	CONDITIONS	MIN	ТҮР	MAX	UNITS
Input Capacitance	CIN			15		pF
DIGITAL OUTPUT (DOUT)						
	Ve	I _{SINK} = 2mA			0.4	v
Output Voltage Low	V _{OL}	I _{SINK} = 4mA			0.8	V
Output Voltage High	V _{OH}	I _{SOURCE} = 1.5mA	DV _{DD} - 0.5			V
DIGITAL OUTPUT (BUSY, PENI	RQ, KEYIRQ, I	R_, C_)				
Output Voltage Low	VOL	I _{SINK} = 0.2mA			0.4	V
Output Voltage High	V _{OH}	ISOURCE = 0.2mA	DV _{DD} - 0.5			V
		POWER REQUIREMENTS	•			
Currely Valtage (Nata 10)	AV _{DD} /	MAX1233	2.7	3	3.6	V
Supply Voltage (Note 12)	DV_DD	MAX1234	4.75	5	5.25	V
		Idle; all blocks shut down		0.5	5	
Analog and Digital Supply	IAVDD +	Only ADC on; f _{SAMPLE} = 20ksps		150	500	
Current	IDVDD	Only DAC on; no load 15		150	230	μA
		Only internal reference on		670	900	
TIMING CHARACTERISTICS						
SCLK Clock Period	tCP		100			ns
SCLK Pulse Width High	tсн		40			ns
SCLK Pulse Width Low	t _{CL}		40			ns
DIN to SCLK Rise Setup	t _{DS}		40			ns
SCLK Rise to DIN Hold	tDH		0			ns
SCLK Fall to DOUT Valid	tdov	$C_{LOAD} = 50 pF$			40	ns
$\overline{\text{CS}}$ Fall to DOUT Enabled	t _{DV}	$C_{LOAD} = 50 pF$			45	ns
CS Rise to DOUT Disabled	tdod	$C_{LOAD} = 50 pF$			40	ns
CS Fall to SCLK Rise	tcss		40			ns
CS Fall to SCLK Ignored	tCSH		0			ns
SCLK Rise to R_/C_ Data Valid	tgpo	C _{LOAD} = 50pF (Note 13)			230	ns
CS Pulse Width High	t _{CSW}		40			ns

Note 1: Tested at $DV_{DD} = AV_{DD} = +2.7V$ (MAX1233), $DV_{DD} = AV_{DD} = +5V$ (MAX1234).

Note 2: Relative accuracy is the deviation of the analog value at any code from its theoretical value after the offset and gain errors have been removed.

Note 3: Offset nulled.

Note 4: Difference between TEMP1 and TEMP2; temperature in $^{\circ}K = (V_{TEMP2} - V_{TEMP1}) \times 2680^{\circ}K/V$. No calibration is necessary.

Note 5: Temperature coefficient is -2.1mV/°C. Determine absolute temperature by extrapolating from a calibrated value.

Note 6: ADC performance is limited by the conversion noise floor, typically 300µV_{P-P}. An external reference below 2.5V can compromise the ADC performance.

Note 7: Guaranteed from code 5 to 255.

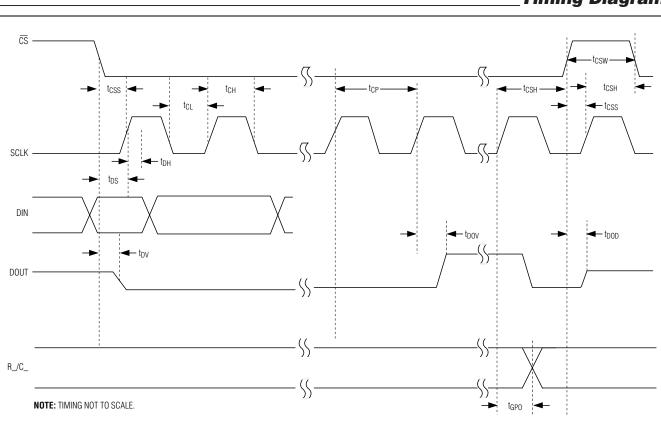
ELECTRICAL CHARACTERISTICS (continued)

 $(DV_{DD} = AV_{DD} = +2.7V \text{ to } +3.6V \text{ (MAX1233)}, DV_{DD} = AV_{DD} = +4.75V \text{ to } +5.25V \text{ (MAX1234)}, \text{ external reference } V_{REF} = 2.5V \text{ (MAX1233)}, V_{REF} = 4.096V \text{ (MAX1234)}; \text{ } \text{f}_{SCLK} = 10MHz, \text{ } \text{f}_{SAMPLE} = 50 \text{ksps}, 12 \text{-bit mode}, 0.1 \mu\text{F} \text{ capacitor at REF}, T_A = -40^{\circ}\text{C} \text{ to } +85^{\circ}\text{C}, \text{ unless otherwise noted}. Typical values are at } T_A = +25^{\circ}\text{C}.)$

Note 8: The offset value extrapolated from the range over which the INL is guaranteed.

- Note 9: Output settling time is measured by stepping from code 5 to 255, and from code 255 to 5.
- **Note 10:** Actual output voltage at full scale is 255/256 × V_{REFDAC}.
- Note 11: Resistance is open when configured as GPIO or in shutdown.
- Note 12: AV_{DD} and DV_{DD} should not differ by more than 300mV.

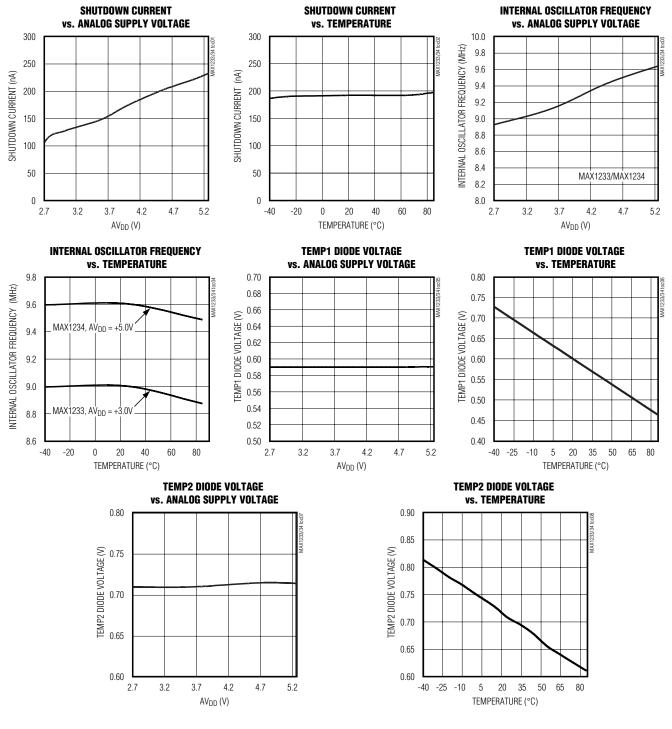
Note 13: When configured as GPIO.



Timing Diagram

Typical Operating Characteristics

 $(AV_{DD} = DV_{DD} = 3V (MAX1233) \text{ or } 5V (MAX1234), \text{ external } V_{REF} = +2.5V (MAX1233), \text{ external } V_{REF} = +4.096V (MAX1234), f_{SCLK} = 10MHz (50\% duty cycle), f_{SAMPLE} = 20ksps, C_{LOAD} = 50pF, 0.1\muF capacitor at REF, T_A = +25°C, unless otherwise noted.)$

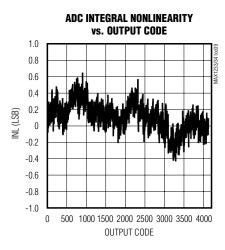


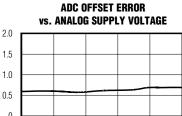
MAX1233/MAX1234

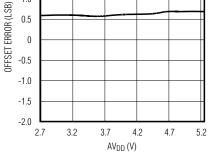
M/IXI/M

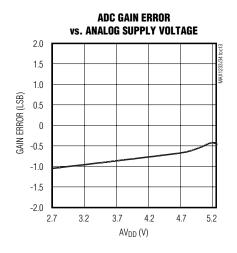
Typical Operating Characteristics (continued)

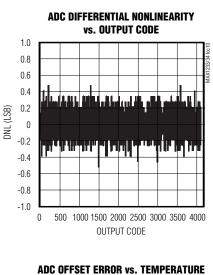
 $(AV_{DD} = DV_{DD} = 3V (MAX1233) \text{ or } 5V (MAX1234), \text{ external } V_{REF} = +2.5V (MAX1233), \text{ external } V_{REF} = +4.096V (MAX1234), f_{SCLK} = 10MHz (50\% duty cycle), f_{SAMPLE} = 20ksps, C_{LOAD} = 50pF, 0.1\muF \text{ capacitor at REF, } T_A = +25^{\circ}C, \text{ unless otherwise noted.}$

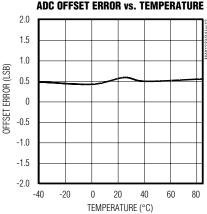




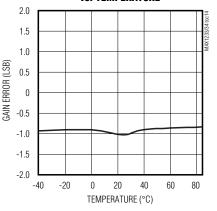








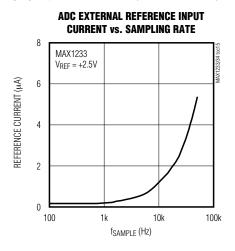
ADC GAIN ERROR vs. TEMPERATURE

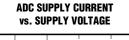




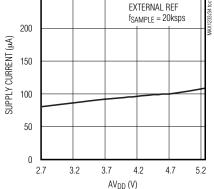
Typical Operating Characteristics (continued)

 $(AV_{DD} = DV_{DD} = 3V (MAX1233) \text{ or } 5V (MAX1234), \text{ external } V_{REF} = +2.5V (MAX1233), \text{ external } V_{REF} = +4.096V (MAX1234), \text{ f}_{SCLK} = 10MHz (50\% duty cycle), \text{ f}_{SAMPLE} = 20ksps, C_{LOAD} = 50pF, 0.1\muF \text{ capacitor at } REF, T_A = +25^{\circ}C, \text{ unless otherwise noted.}$

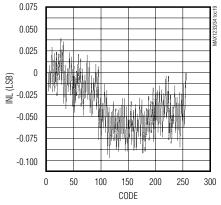




250



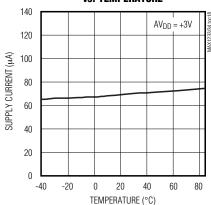




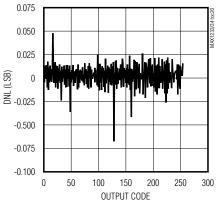
vs. SAMPLING RATE

ADC SUPPLY CURRENT

ADC SUPPLY CURRENT vs. TEMPERATURE

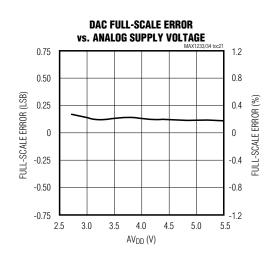


DAC DIFFERENTIAL NONLINEARITY vs. output code

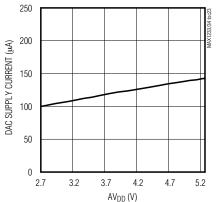


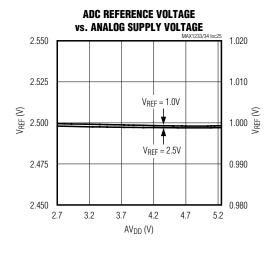
Typical Operating Characteristics (continued)

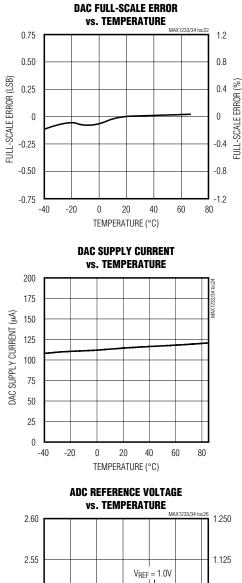
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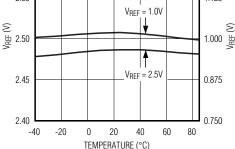








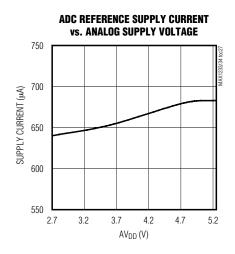


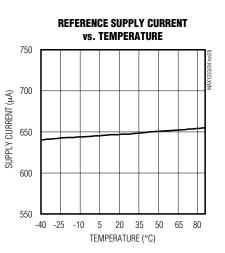




Typical Operating Characteristics (continued)

 $(AV_{DD} = DV_{DD} = 3V (MAX1233) \text{ or } 5V (MAX1234), \text{ external } V_{REF} = +2.5V (MAX1233), \text{ external } V_{REF} = +4.096V (MAX1234), \text{ } f_{SCLK} = 10MHz (50\% \text{ duty cycle}), \text{ } f_{SAMPLE} = 20 \text{ksps}, \text{ } C_{LOAD} = 50 \text{pF}, 0.1 \mu\text{F} \text{ capacitor at REF}, \text{ } T_{A} = +25^{\circ}\text{C}, \text{ unless otherwise noted.})$





MAX1233/MAX1234

Pin Description

PIN	NAME	FUNCTION
1	DV _{DD}	Positive Digital Supply Voltage, +2.7V to +3.6V for MAX1233, +4.75V to +5.25V for MAX1234. Bypass with a 0.1μ F capacitor. Must be within 300mV of AV _{DD} .
2	AV _{DD}	Positive Analog Supply Voltage, +2.7V to +3.6V for MAX1233, +4.75V to +5.25V for MAX1234. Bypass with a 0.1μ F capacitor. Must be within 300mV of DV _{DD} .
3*	X+	X+ Position Input
4*	Y+	Y+ Position Input
5*	Х-	X- Position Input
6*	Y-	Y- Position Input
7	GND	Analog and Digital Ground
8*	BAT1	Battery Monitoring Input 1. Measures battery voltages up to 6V.
9*	BAT2	Battery Monitoring Input 2. Measures battery voltages up to 6V.
10*	AUX1	Auxiliary Analog Input 1 to ADC. Measures analog voltages from zero to VREF.
11*	AUX2	Auxiliary Analog Input 2 to ADC. Measures analog voltages from zero to VREF.
12	REF	Voltage Reference Output/Input. Reference voltage for analog-to-digital conversion. In internal reference mode, the reference buffer provides a 2.5V or 1.0V nominal output. In external reference mode, apply a reference voltage between 1.0V and AV _{DD} . Bypass REF to GND with a 0.1 μ F capacitor in the external reference mode only.
13	DACOUT	DAC Voltage Output; 0.9 × AV _{DD} Full Scale
14	R4	Keypad Row 4. Can be reconfigured as GPIO3.
15	R3	Keypad Row 3. Can be reconfigured as GPIO2.
16	R2	Keypad Row 2. Can be reconfigured as GPIO1.
17	R1	Keypad Row 1. Can be reconfigured as GPIO0.
18	C1	Keypad Column 1. Can be reconfigured as GPIO4.

Pin Description (continued)

PIN	NAME	FUNCTION
19	C2	Keypad Column 2. Can be reconfigured as GPIO5.
20	C3	Keypad Column 3. Can be reconfigured as GPIO6.
21	C4	Keypad Column 4. Can be reconfigured as GPIO7.
22	KEYIRQ	Active-Low Keypad Interrupt. KEYIRQ is low when a key press is detected.
23	PENIRQ	Active-Low Pen Touch Interrupt. PENIRQ is low when a screen touch is detected.
24	DOUT	Serial Data Output. Data is clocked out at SCLK falling edge. High impedance when $\overline{\text{CS}}$ is high.
25	BUSY	Active-Low Busy Output. BUSY goes low and stays low during each functional operation. The host controller should wait until BUSY is high again before using the serial interface.
26	DIN	Serial Data Input. Data is clocked in on the rising edge of SCLK.
27	SCLK	Serial Clock Input. Clocks data in and out of the serial interface and sets the conversion speed (duty cycle must be 30% to 70%).
28	CS	Active-Low Chip Select. Data is not clocked into DIN unless \overline{CS} is low. When \overline{CS} is high, DOUT is high impedance.
_	EP	Exposed Pad. Internally connected to GND. Connect to a large ground plane to maximize thermal performance. Not intended as an electrical connection point.

*ESD protected: ±8kV Contact, ±15kV Air.

Detailed Description

The MAX1233/MAX1234 are 4-wire touch-screen controllers. Figure 1 shows the functional diagram of the MAX1233/MAX1234. Each device includes a 12-bit sampling ADC, 8-bit voltage output DAC, keypad scanner that can also be configured as a GPIO, internal clock, reference, temperature sensor, two battery monitor inputs, two auxiliary analog inputs, SPI/QSPI/ MICROWIRE-compatible serial interface, and low onresistance switches for driving touch screens.

The 16-bit register inside the MAX1233/MAX1234 allows for easy control and stores results that can be read at any time. The BUSY output indicates that a functional operation is in progress. The PENIRQ and KEYIRQ outputs, respectively, indicate that a screen touch or a key press has occurred.

Touch-Screen Operation

The 4-wire touch-screen controller works by creating a voltage gradient across the vertical or horizontal resistive touch screen connected to the analog inputs of the MAX1233/MAX1234, as shown in Figure 2. The voltage across the touch-screen panels is applied through internal MOSFET switches that connect each resistive layer to AV_{DD} and ground. For example, to measure the Y position when a pointing device presses on the touch screen, the Y+ and Y- drivers are turned on, connecting one side of the vertical resistive layer to AV_{DD} and the other side to ground. The horizontal resistive layer functions as a sense line. One side of this resistive layer gets connected to the X+ input, while the other side is left

open or floating. The point where the touch screen is pressed brings the two resistive layers in contact and creates a voltage-divider at that point. The data converter senses the voltage at the point of contact through the X+ input and digitizes it.

12-Bit ADC

Analog Inputs

Figure 3 shows a block diagram of the ADC's analog input section including the input multiplexer, the differential input, and the differential reference. The input multiplexer switches between X+, X-, Y+, Y-, AUX1, AUX2, BAT1, BAT2, and the internal temperature sensor.

The time required for the T/H to acquire an input signal is a function of how quickly its input capacitance is charged. If the input signal's source impedance is high, the acquisition time lengthens, and more time must be allowed. The acquisition time (t_{ACQ}) is the maximum time the device takes to acquire the input signal to 12bit accuracy. Configure t_{ACQ} by writing to the ADC control register. See Table 1 for the maximum input signal source impedance (R_{SOURCE}) for complete settling during acquisition.

Accommodate higher source impedances by placing a 0.1μ F capacitor between the analog input and GND.

Input Bandwidth

The ADC's input-tracking circuitry has a 0.5MHz smallsignal bandwidth. To avoid high-frequency signals being aliased into the frequency band of interest, antialias filtering is recommended.



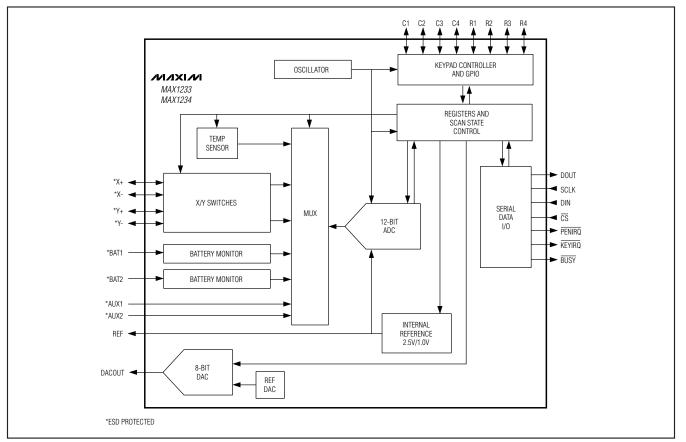


Figure 1. Block Diagram

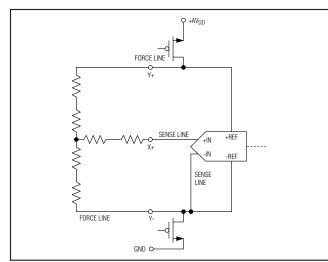


Figure 2. Touch-Screen Measurement

Table 1. Maximum Input SourceImpedance

ACQUISITION TIME (µs)	RESOLUTION (BITS)	MAXIMUM R _{SOURCE} FOR COMPLETE SETTLING DURING ACQUISITION (kΩ)
1.5	8	2.6
1.5	10	2.0
1.5	12	1.5
5.0	8	23
5.0	10	19
5.0	12	15
95	8	560
95	10	470
95	12	400

13

MAX1233/MAX1234



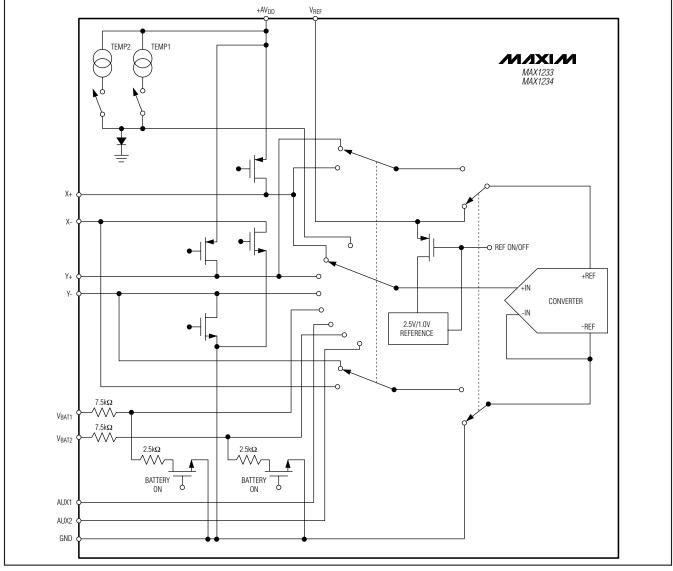


Figure 3. Simplified Diagram of Analog Input Section

Analog Input Protection

Internal protection diodes that clamp the analog input to AV_{DD} and GND allow the analog input pins to swing from GND - 0.3V to AV_{DD} + 0.3V without damage. Analog inputs must not exceed AV_{DD} by more than 50mV or be lower than GND by more than 50mV for accurate conversions. If an off-channel analog input voltage exceeds the supplies, limit the input current to 50mA. **All analog inputs are also fully ESD protected**

to \pm 8kV, using the Contact-Discharge method and \pm 15kV using the Air-Gap method specified in IEC-1000-4-2.

Reference for ADC

Internal Reference

The MAX1233/MAX1234 offer an internal voltage reference for the ADC that can be set to +1.0V or +2.5V. The MAX1233/MAX1234 typically use the internal reference for battery monitoring, temperature measurement, and for



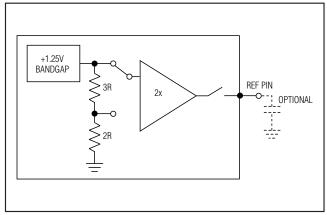


Figure 4. Block Diagram of the Internal Reference

measurement of the auxiliary inputs. Figure 4 shows the on-chip reference circuitry of the MAX1233/MAX1234.

Set the internal reference voltage by writing to the RFV bits in the ADC control register (see Tables 4, 5, and 12). The MAX1233/MAX1234 can accept an external reference connected to REF for ADC conversion.

External Reference

The MAX1233/MAX1234 can accept an external reference connected to the REF pin for ADC conversions. The internal reference should be disabled (RES1 = 1) when using an external reference. At a conversion rate of 50ksps, an external reference at REF must deliver up to 15µA of load current and have 50Ω or less output impedance. If the external reference has high output impedance or is noisy, bypass it close to the REF pin with a 0.1µF capacitor.

Selecting Internal or External Reference

Set the type of reference being used by programming the ADC control register. To select the internal reference, clock zeros into bits [A/D3:A/D0] and a zero to bit RES1, as shown in the *Control Registers* section. To change to external reference mode, clock zeros into bits [A/D3:A/D0] and a one to bit RES1. See Table 13 for more information about selecting an internal or external reference for the ADC.

Reference Power Modes

Auto Power-Down Mode (RES1 = RES0 = 0)

The MAX1233/MAX1234 are in auto power-down mode at initial power-up. Set the RES1 and RES0 bits to zero to use the MAX1233/MAX1234 in the auto power-down mode. In this mode, the internal reference is normally off. When a command to perform a battery measurement, temperature measurement, or auxiliary input measurement is written to the ADC control register, the device powers on the internal reference, waits for the internal reference to settle, completes the requested scan, and powers down the internal reference. The reference power delay depends upon the ADC resolution selected (see Table 8). Do not bypass REF with an external capacitor when performing scans in auto power-down mode.

Full-Power Mode (RES1 = 0, RES0 = 1)

In the full-power mode, the RES1 bit is set LOW and RES0 bit is set HIGH. In this mode, the device is powered up and the internal ADC reference is always ON. The MAX1233/MAX1234 internal reference remains fully powered after completing a scan.

Internal Clock

The MAX1233/MAX1234 operate from an internal oscillator, which is accurate to within 20% of the 10MHz specified clock rate. The internal oscillator controls the timing of the acquisition, conversion, touch-screen settling, reference power-up, and keypad debounce times.

8-Bit DAC

The MAX1233/MAX1234 have a voltage-output, true 8-bit monotonic DAC with less than 1LSB integral nonlinearity error and less than 1LSB differential nonlinearity error. It requires a supply current of only 150 μ A (typ) and provides a buffered voltage output. The DAC is at midscale code at power-up and remains there until a new code is written to the DAC register. During shutdown, the DAC's output is pulled to ground with a 1M Ω load.

The internal DAC can be used in various system applications such as LCD/TFT-bias control, automatic tuning (VCO), power amplifier bias control, programmable threshold levels, and automatic gain control (AGC).

The 8-bit DAC in the MAX1233/MAX1234 employs a current-steering topology as shown in Figure 5. At the core of this DAC is a reference voltage-to-current converter (V/I) that generates a reference current. This current is mirrored to 255 equally weighted current sources. DAC switches control the outputs of these current mirrors so that only the desired fraction of the total current-mirror currents is steered to the DAC output. The current is then converted to a voltage across a resistor, and the output amplifier buffers this voltage.

DAC Output Voltage

The 8-bit DAC code is binary unipolar with $1LSB = (V_{REF}/256)$. The DAC has a full-scale output voltage of $(0.9 \times AV_{DD} - 1LSB)$.

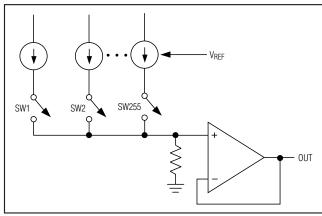


Figure 5. DAC Current-Steering Topology

Output Buffer

The DAC voltage output is an internally buffered unitygain follower that slews at up to ± 0.4 V/µs. The output can swing from zero to full scale. With a 1/4FS to 3/4FS output transition, the amplifier output typically settles to 1/2LSB in less than 5µs when loaded with 10k Ω in parallel with 50pF. The buffer amplifier is stable with any combination of resistive loads >10k Ω and capacitive loads <50pF.

Power-On Reset

All registers of the MAX1233/MAX1234 power up at a default zero state, except the DAC data register, which is set to 10000000, so the output is at midscale.

Keypad Controller and GPIO

The keypad controller is designed to interface a matrixtype 4 rows × 4 columns (16 keys or fewer) keypad to a host controller. The KEY control register controls keypad interrupt, keypad scan, and keypad debounce times. The KeyMask and ColumnMask registers enable masking of a particular key or an entire column of the keypad when they are not in use. The MAX1233/MAX1234 offer two keypad data registers. KPData1 is the pending register. KPData2 holds keypad scan results of only the unmasked keys. If 12 or fewer keys are being monitored, one or more of the row/column pins of the MAX1233/MAX1234 can be software programmed as GPIO pins.

Touch-Screen Detection

Touch-screen detection can be enabled or disabled by writing to the ADC control register as shown in Table 4. Touch-screen detection is disabled at initial power-up. Once touch-screen detection is enabled, the Y- driver is on and the Y- pin is connected to GND. The X+ pin is internally pulled to AV_{DD} through a $1M\Omega$ resistor as

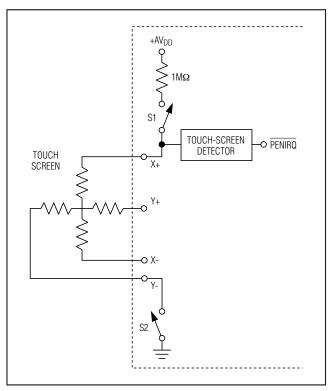


Figure 6. Touch-Screen Detection Block Diagram

shown in Figure 6. When the screen is touched, the X+ pin is pulled to GND through the touch screen and a touch is detected.

When the 1M Ω pullup resistor is first connected, the X+ pin can be floating near ground. To prevent false touch detection in this case, the X+ pin is precharged high for 0.1 μ s using the 7 Ω PMOS driver before touch detection begins.

Key-Press Detection

Key-press detection can be enabled or disabled by writing to the keypad control register as shown in Table 17. Key-press detection is disabled at initial power-up. Once key-press detection is enabled, the C_ pins are internally connected to DV_{DD} and the R_ pins are internally pulled to GND through a 16k Ω resistor. When a key is pressed, the associated row pin is pulled to DV_{DD} and the key press is detected. Figure 7 shows the key-press detection circuitry.

Interrupts

PEN Interrupt Request (PENIRQ)

The PENIRQ output can be used to alert the host controller of a screen touch. The PENIRQ output is normally high and goes low after a screen touch is detected.



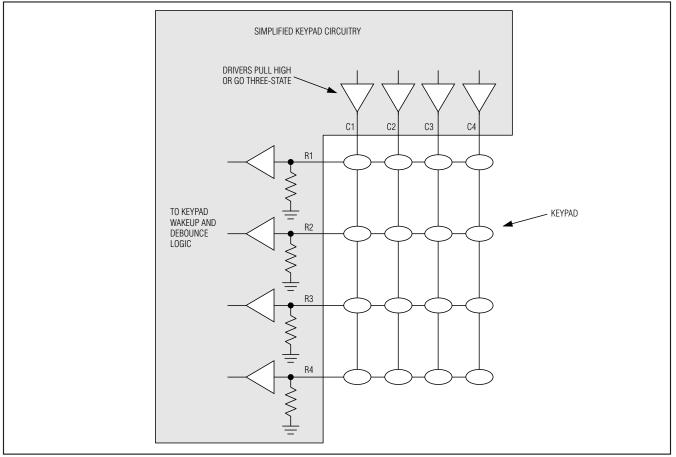


Figure 7. Key-Press Detection Circuitry

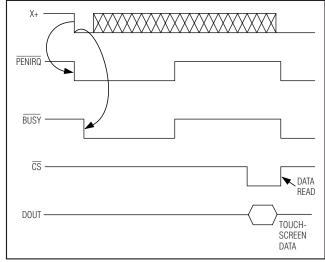


Figure 8a. Timing Diagram for Touch-Initiated Screen Scan

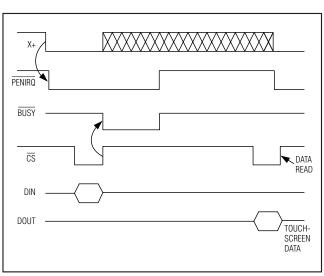


Figure 8b. Timing Diagram for Host-Initiated Screen Scan

PENIRQ returns high only after a touch-screen scan is completed. PENIRQ does not go low again until one of the touch-screen data registers is read. Figures 8a and 8b show the timing diagrams for the PENIRQ pin.

Keypad Interrupt Request (KEYIRQ)

The KEYIRQ output can be used to alert the host controller of a key press. The KEYIRQ output is normally high and goes low after a key press is detected. KEYIRQ returns high only after a key-press scan is completed. KEYIRQ does not go low again until one of the key-press data registers is read. Figures 9a and 9b show the timing diagrams for the KEYIRQ pin.

Busy Indicator (BUSY)

BUSY informs the host processor that a scan is in progress. BUSY is normally high and goes low and stays low during each functional operation. The host controller should wait until BUSY is high again before using the serial interface.

Digital Interface The MAX1233/MAX1234 interface to the host controller through a standard 3-wire serial interface at up to 10MHz. DIN and \overline{CS} are the digital inputs to the MAX1233/MAX1234. DOUT is the serial data output. Data is clocked out at the SCLK falling edge and is high impedance when \overline{CS} is high. When performing an ADC scan, CS must de-assert high before the end of the first conversion, otherwise the conversion results will not be stored. PENIRQ and KEYIRQ communicate interrupts from the touch-screen and keypad controllers to the host processor when a screen touch or a key press is detected. BUSY informs the host processor that a scan is in progress. In addition to these digital I/Os, the row and column pins of the keypad controller can be programmed as GPIO pins.

Communications Protocol

The MAX1233/MAX1234 are controlled by reading from and writing to registers through the 3-wire serial interface. These registers are addressed through a 16-bit command that is sent prior to the data. The command is shown in Table 2.

The first 16 bits after the falling edge of \overline{CS} contain the command word. The command word begins with an R/\overline{W} bit, which specifies the direction of data flow on the serial bus. Bits 14 through 7 are reserved for future use. Bit 6 specifies the page of memory in which the

Table 2. Command Word Format

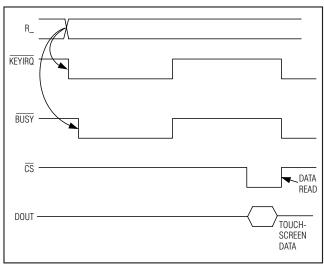


Figure 9a. Timing Diagram for Key-Press-Initiated Debounce Scan

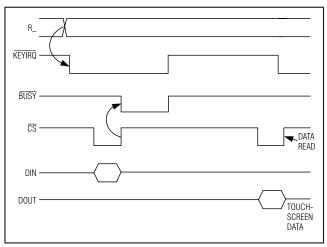


Figure 9b. Timing Diagram for Host-Initiated Keypad Debounce Scan

desired register is located. The last 6 bits specify the address of the desired register. The next 16 bits of data are read from or written to the address specified in the command word. After 32 clock cycles, the interface automatically increments its address pointer and continues reading or writing until the rising edge of \overline{CS} , or until it reaches the end of the page.

BIT15 MSB	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0 LSB
R/W	RES	RES	RES	RES	RES	RES	RES	RES	PAGE	ADD5	ADD4	ADD3	ADD2	ADD1	ADD0

WRITE COMMAND (HEX)	READ COMMAND (HEX)	REGISTER NAME	BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	віто
-	0x8000	Х	0	0	0	0	X11	X10	X9	X8	X7	X6	X5	X4	X3	X2	X1	X0
—	0x8001	Y	0	0	0	0	Y11	Y10	Y9	Y8	Y7	Y6	Y5	Y4	Y3	Y2	Y1	Y0
_	0x8002	Z1	0	0	0	0	Z1_11	Z1_10	Z1_9	Z1_8	Z1_7	Z1_6	Z1_5	Z1_4	Z1_3	Z1_2	Z1_1	Z1_0
—	0x8003	Z2	0	0	0	0	Z2_11	Z2_10	Z2_9	Z2_8	Z2_7	Z2_6	Z2_5	Z2_4	Z2_3	Z2_2	Z2_1	Z2_0
_	0x8004	KPD	K15	K14	K13	K12	K11	K10	K9	K8	K7	K6	K5	K4	K3	K2	K1	K0
_	0x8005	BAT1	0	0	0	0	B1_11	B1_10	B1_9	B1_8	B1_7	B1_6	B1_5	B1_4	B1_3	B1_2	B1_1	B1_0
_	0x8006	BAT2	0	0	0	0	B2_11	B2_10	B2_9	B2_8	B2_7	B2_6	B2_5	B2_4	B2_3	B2_2	B2_1	B2_0
_	0x8007	AUX1	0	0	0	0	A1_11	A1_10	A1_9	A1_8	A1_7	A1_6	A1_5	A1_4	A1_3	A1_2	A1_1	A1_0
—	0x8008	AUX2	0	0	0	0	A2_11	A2_10	A2_9	A2_8	A2_7	A2_6	A2_5	A2_4	A2_3	A2_2	A2_1	A2_0
—	0x8009	TEMP1	0	0	0	0	T1_11	T1_10	T1_9	T1_8	T1_7	T1_6	T1_5	T1_4	T1_3	T1_2	T1_1	T1_0
_	0x800A	TEMP2	0	0	0	0	T2_11	T2_10	T2_9	T2_8	T2_7	T2_6	T2_5	T2_4	T2_3	T2_2	T2_1	T2_0
0x000B	0x800B	DAC data	0	0	0	0	0	0	0	0	DA7	DA6	DA5	DA4	DA3	DA2	DA1	DA0
0x000F	0x800F	GPIO data	GPD7	GPD6	GPD5	GPD4	GPD3	GPD2	GPD1	GPD0	0	0	0	0	0	0	0	0
_	0x8010	KPData1	K1_15	K1_14	K1_13	K1_12	K1_11	K1_10	K1_9	K1_8	K1_7	K1_6	K1_5	K1_4	K1_3	K1_2	K1_1	K1_0
—	0x8011	KPData2	K2_15	K2_14	K2_13	K2_12	K2_11	K2_10	K2_9	K2_8	K2_7	K2_6	K2_5	K2_4	K2_3	K2_2	K2_1	K2_0
0x0040	0x8040	ADC control	PENSTS	ADSTS	A/D3	A/D2	A/D1	A/D0	RES1	RES0	AVG1	AVG0	CNR1	CNR0	ST2	ST1	ST0	RFV
0x0041	0x8041	KEY control	KEYSTS1	KEYSTS0	DBN2	DBN1	DBN0	HLD2	HLD1	HLD0	0	0	0	0	0	0	0	0
0x0042	0x8042	DAC control	DAPD	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
0x004E	0x804E	GPIO pullup	PU7	PU6	PU5	PU4	PU3	PU2	PU1	PU0	0	0	0	0	0	0	0	0
0x004F	0x804F	GPIO control	GP7	GP6	GP5	GP4	GP3	GP2	GP1	GP0	OE7	OE6	OE5	OE4	OE3	OE2	OE1	OE0
0x0050	0x8050	KPKeyMask	KM15	KM14	KM13	KM12	KM11	KM10	KM9	KM8	KM7	KM6	KM5	KM4	KM3	KM2	KM1	KM0
0x0051	0x8051	KPColumnMask	CM4	CM3	CM2	CM1	0	0	0	0	0	0	0	0	0	0	0	0

Table 3. Register Summary

Note: All other registers are reserved and should always be 0. Power-on reset state is DAC data at midscale (0x0080), all other registers are 0.

Memory Map

In order to read the entire first page of memory, for example, the host processor must send the MAX1233/MAX1234 the command 0x8000_H. The MAX1233/MAX1234 then begin clocking out 16-bit data starting with the X-data register. In order to write to the second page of memory, the host processor sends the MAX1233/MAX1234 the command 0x0040_H. The succeeding data is then written in 16-bit words beginning with the ADC control register. Figures 10a and 10b show a complete write and read operation, respectively, between the processor and the MAX1233/MAX1234.

The MAX1233/MAX1234s' internal memory is divided into two pages—one for data and one for control, each of which contains thirty-two 16-bit registers.

Control Registers

Table 3 provides a summary of all registers and bit locations of the MAX1233/MAX1234.

ADC Control Register

The ADC measures touch position, touch pressure, battery voltage, auxiliary analog inputs, and temperature. The ADC control register determines which input is selected and converted. Tables 4 and 5 show the format and bit descriptions for the ADC control register.

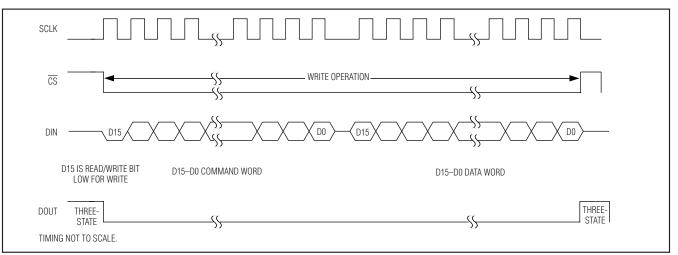


Figure 10a. Timing Diagram of Write Operation

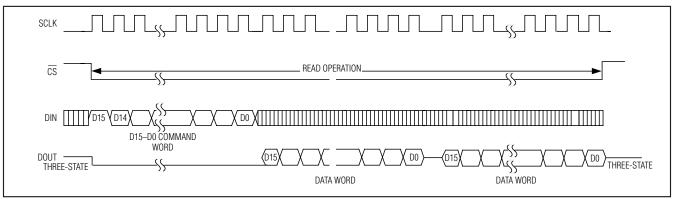


Figure 10b. Timing Diagram of Read Operation

Table 4. ADC Control Register (Write 0x0040/Read 0x8040)

BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
PENSTS	ADSTS	A/D3	A/D2	A/D1	A/D0	RES1	RES0	AVG1	AVG0	CNR1	CNR0	ST2	ST1	ST0	RFV

/N/IXI/N

Bits 14-15: Pen Interrupt Status and ADC Status Bits

These bits are used to control or monitor ADC scans.

Bits 10-13: ADC Scan Select

These bits control which input to convert and which converter mode is used. The bits are identical regardless of a read or write. See Table 7 for details about using these bits.

Bits 8-9: ADC Resolution Control

These bits specify the ADC resolution and are identical regardless of read or write. Table 8 shows how to use these bits to set the resolution.

Bits 6-7: Converter Averaging Control

These bits specify the number of data averages the converter performs. Table 9 shows how to program for the desired number of averages. When averaging is used, ADSTS and BUSY indicate the converter is busy until all conversions needed for the averaging finish. These bits are identical, regardless of read or write.

Bits 4-5: ADC Conversion Rate Control

These bits specify the internal conversion rate, which the ADC uses to perform a single conversion, as shown in Table 10. Lowering the conversion rate also reduces power consumption. These bits are identical, regardless of read or write.

Table 5. ADC Control Register Bit Descriptions (Write 0x0040/Read 0x8040)

BIT	NAME	DESCRIPTION
15 (MSB)	PENSTS	Read: pen interrupt status; Write: sets interrupt initiated touch-screen scans
14	ADSTS	Read: ADC status; Write: stops ADC
13	A/D3	Selects ADC scan functions
12	A/D2	Selects ADC scan functions
11	A/D1	Selects ADC scan functions
10	A/D0	Selects ADC scan functions
9	RES1	Controls ADC resolution
8	RES0	Controls ADC resolution
7	AVG1	Controls ADC result averaging
6	AVG0	Controls ADC result averaging
5	CNR1	Controls ADC conversion rate
4	CNR0	Controls ADC conversion rate
3	ST2	Controls touch-screen settling wait time
2	ST1	Controls touch-screen settling wait time
1	ST0	Controls touch-screen settling wait time
0 (LSB)	RFV	Chooses 1.0V or 2.5V reference

Table 6. ADSTS Bit Operation

PENSTS	ADSTS	READ FUNCTION	WRITE FUNCTION
0	0	No screen touch detected; scan or conversion in progress	Performs one scan and waits to detect a screen touch. Upon detection, issues an interrupt and waits until told to scan by the host controller.
1	0	Screen touch detected; scan or conversion in progress	Stops any ongoing scan and waits to detect a screen touch. Upon detection, issues an interrupt and performs a scan.
0	1	No screen touch detected; data available	Stops any ongoing scan and waits to detect a screen touch. Upon detection, issues an interrupt and waits until told to scan by the host controller.
1	1	Screen touch detected; data available	Stops any ongoing scan and powers down the screen touch detection circuit. No screen touches are detected in this mode.



Table 7. ADC Scan Select (Touch Screen, Battery, Auxiliary Channels, and Temperature)

A/D3	A/D2	A/D1	A/D0	FUNCTION
0	0	0	0	Configures the ADC reference as selected by RES [1:0] bits as shown in Table 13. No measurement is performed.
0	0	0	1	Measures X/Y touch position and returns results to the X and Y data registers.
0	0	1	0	Measures X/Y touch position and Z1/Z2 touch pressure and returns results to the X, Y, Z1, and Z2 data registers.
0	0	1	1	Measures X touch position and returns results to the X data register.
0	1	0	0	Measures Y touch position and returns results to the Y data register.
0	1	0	1	Measures Z1/Z2 touch pressure and returns results to the Z1 and Z2 data register.
0	1	1	0	Measures Battery Input 1 through a 4:1 divider and returns results to the BAT1 data register.
0	1	1	1	Measures Battery Input 2 through a 4:1 divider and returns results to the BAT2 data register.
1	0	0	0	Measures Auxiliary Input 1 and returns results to the AUX1 data register.
1	0	0	1	Measures Auxiliary Input 2 and returns results to the AUX2 data register.
1	0	1	0	Measures temperature (single ended) and returns results to the TEMP1 data register.
1	0	1	1	Measures Battery Input 1, Battery Input 2, Auxiliary Input 1, Auxiliary Input 2, and temperature (differential), and returns results to the appropriate data registers.
1	1	0	0	Measures temperature (differential) and returns results to the TEMP1 and TEMP2 data registers.
1	1	0	1	Turns on Y+, Y- drivers. No measurement is performed.
1	1	1	0	Turns on X+, X- drivers. No measurement is performed.
1	1	1	1	Turns on Y+, X- drivers. No measurement is performed.

Table 8. ADC Resolution Control

RES1	RES0	ADC RESOLUTION	INTERNALLY TIMED REFERENCE POWER-UP DELAY* (µs)
0	0	8 bit	31
0	1	8 bit	31
1	0	10 bit	37
1	1	12 bit	44

*Applicable only for temperature, battery, or auxiliary measurements in auto power-up reference mode.

Table 9. ADC Averaging Control

AVG1	AVG0	FUNCTION
0	0	No data averages (default)
0	1	4 data averages
1	0	8 data averages
1	1	16 data averages

Table 10. ADC Conversion Rate Control

CNR1	CNR0	FUNCTION
0	0	3.5µs/sample (1.5µs acquisition, 2µs conversion)
0	1	3.5µs/sample (1.5µs acquisition, 2µs conversion)
1	0	10µs/sample (5µs acquisition, 5µs conversion)
1	1	100µs/sample (95µs acquisition, 5µs conversion)

Bits 1-3: Touch-Screen Settling Time Control

These bits specify the time delay from pen-touch detection to a conversion start. This allows the selection of the appropriate settling time for the touch screen being used. Table 11 shows how to set the settling time. These bits are identical, regardless of read or write.

Bit 0: ADC Internal Reference Voltage Control This bit selects the ADC internal reference voltage, either +1.0V or +2.5V. This bit is identical, regardless of read or write. The reference control bit is shown in Table 12.

Table 11. Touch-Screen Settling Time Control*

ST2	ST1	ST0	SETTLING TIME
0	0	0	Settling time: 0µs
0	0	1	Settling time: 100µs
0	1	0	Settling time: 500µs
0	1	1	Settling time: 1ms
1	0	0	Settling time: 5ms
1	0	1	Settling time: 10ms
1	1	0	Settling time: 50ms
1	1	1	Settling time: 100ms

*Applicable only for X, Y, Z1, and Z2 measurements.

Table 12. ADC Reference Control Bit

RFV	FUNCTION
0	+1.0V reference
1	+2.5V reference

Internal ADC Reference Power-Down Control

The ADC control register controls the power setting of the internal ADC reference. Zeros must be written to bits A/D3–A/D0 to control internal reference power-up followed by the appropriate logic at the RES1 and RES0 bits. Table 13 shows the internal ADC reference powerdown control.

DAC Control Register

The MSB in this control register determines the powerdown control of the on-board DAC. Table 14 shows the DAC control register. Writing a zero to bit 15 (DAPD) powers up the DAC, while writing a 1 powers down the DAC. Table 15 describes the DAC control register contents, while Table 16 shows the DAC power-down bit.

Keypad Control Registers

The keypad control register, keypad mask register, and keypad column mask control register control the keypad scanner in the MAX1233/MAX1234. The keypad control register (Table 17) controls scanning and debouncing, while the keypad mask register (Table 22) and the keypad column mask control register (Table 24),

Table 15. DAC Control RegisterDescriptions

BIT	NAME	DESCRIPTION
15 (MSB)	DAPD	DAC powered down
[14:0]	0	Reserved

Table 16. DAC Power-Down Bit

DAPC	FUNCTION
0	DAC powered up
1	DAC powered down

Table 13. Internal ADC Reference Auto Power-Up Control

[A/D3:A/D0]	RES1	RES0	ADC REFERENCE SOURCE	ADC REFERENCE POWER MODE
0000	0	0	Internal	Power up, wait for reference to settle, and power down again for each temperature, battery, or auxiliary scan (auto power-up mode)
0000	0	1	Internal	Always powered up
0000	1	0	External	Always powered down
0000	1	1	External	Always powered down

Table 14. DAC Control Register (Write 0x0042/Read 0x8042)

BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
DAPD	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

Table 17. Keypad Control Register (Write 0x0041/Read 0x8041)

BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
KEYSTS1	KEYSTS0	DBN2	DBN1	DBN0	HLD2	HLD	HLD	0	0	0	0	0	0	0	0

Table 18. Keypad Control Register Bit Descriptions (Write 0x0041/Read 0x8041)

BIT	NAME	DESCRIPTION
15 (MSB)	KEYSTS1	Read: keypad interrupt status; Write: set interrupt initiated keypad scans
14	KEYSTS0	Read: keypad scan status; Write: stop keypad scan
13	DBN2	Keypad debounce time control
12	DBN1	Keypad debounce time control
11	DBN0	Keypad debounce time control
10	HLD2	Keypad hold time control
9	HLD1	Keypad hold time control
8	HLD0	Keypad hold time control
[7:0]	0	Reserved

Table 19. KEYSTS1/KEYSTS0 Functions

KEYSTS1	KEYSTS0	READ FUNCTION	WRITE FUNCTION
0	0	No button press detected; scan or debounce in progress	Scans keypad once and waits to detect a button press. Upon detection, issues an interrupt and waits for the host's instruction before scanning.
1	0	Button press detected; scan or debounce in progress	Stops any ongoing scan and waits to detect a button press. Upon detection, issues an interrupt and scans the keypad.
0	1	No button press detected; data available	Stops any ongoing scan and waits to detect a button press. Upon detection, issues an interrupt and waits for the host's instruction before scanning.
1	1	Button press detected; data available	Stops any ongoing scan and powers down the button press detection circuit. No button presses are detected in this mode.

Table 20. Keypad Debounce Time Control

DBN2	DBN1	DBN0	FUNCTION (ms)
0	0	0	Debounce time: 2
0	0	1	Debounce time: 10
0	1	0	Debounce time: 20
0	1	1	Debounce time: 50
1	0	0	Debounce time: 60
1	0	1	Debounce time: 80
1	1	0	Debounce time: 100
1	1	1	Debounce time: 120

allowing certain keys to be masked from detection. Tables 18–21 show the programmable bits of the keypad control register. Tables 23, 24, and 25 show the programmable bits of the keypad mask registers. The Keypad Controller and GPIO section provides more details.

GPIO Control Register

The GPIO control register and the GPIO pullup register allow the keypad controller's row and column inputs to be configured as up to eight parallel I/O pins. Tables 26 and 27 show the GPIO control register layout and control register descriptions. Tables 28 and 29 show the GPIO pullup disable register and associated descriptions. For more information, see the Applications Information section.

HLD2 HLD1 HLD0 FUNCTION 0 0 0 If a button is held, wait 100µs before beginning next debounce scan 0 0 1 If a button is held, wait 1 debounce time before beginning the next debounce scan 0 0 1 If a button is held, wait 2 debounce times before beginning the next debounce scan If a button is held, wait 3 debounce times before beginning the next debounce scan 0 1 1 If a button is held, wait 4 debounce times before beginning the next debounce scan 1 0 0 1 0 1 If a button is held, wait 5 debounce times before beginning the next debounce scan 1 1 0 If a button is held, wait 6 debounce times before beginning the next debounce scan 1 1 1 If a button is held, wait 7 debounce times before beginning the next debounce scan

Table 21. Keypad Hold Time Control

Table 22. Keypad Key Mask Register Bit Descriptions (Write 0x0050/Read 0x8050)

BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
KM15	KM14	KM13	KM12	KM11	KM10	KM9	KM8	KM7	KM6	KM5	KM4	КМЗ	KM2	KM1	KM0

Table 23. Keypad Key Mask Register Bit Descriptions (Write 0x0050/Read 0x8050)

BITNAMEDESCRIPTION15KM15Mask status register data update on individual key for row 4, column 414KM14Mask status register data update on individual key for row 3, column 413KM13Mask status register data update on individual key for row 2, column 412KM12Mask status register data update on individual key for row 1, column 411KM11Mask status register data update on individual key for row 4, column 310KM10Mask status register data update on individual key for row 3, column 39KM9Mask status register data update on individual key for row 2, column 37KM7Mask status register data update on individual key for row 4, column 2	
14KM14Mask status register data update on individual key for row 3, column 413KM13Mask status register data update on individual key for row 2, column 412KM12Mask status register data update on individual key for row 1, column 411KM11Mask status register data update on individual key for row 4, column 310KM10Mask status register data update on individual key for row 3, column 39KM9Mask status register data update on individual key for row 2, column 38KM8Mask status register data update on individual key for row 1, column 3	
13KM13Mask status register data update on individual key for row 2, column 412KM12Mask status register data update on individual key for row 1, column 411KM11Mask status register data update on individual key for row 4, column 310KM10Mask status register data update on individual key for row 3, column 39KM9Mask status register data update on individual key for row 2, column 38KM8Mask status register data update on individual key for row 1, column 3	
12KM12Mask status register data update on individual key for row 1, column 411KM11Mask status register data update on individual key for row 4, column 310KM10Mask status register data update on individual key for row 3, column 39KM9Mask status register data update on individual key for row 2, column 38KM8Mask status register data update on individual key for row 1, column 3	
11KM11Mask status register data update on individual key for row 4, column 310KM10Mask status register data update on individual key for row 3, column 39KM9Mask status register data update on individual key for row 2, column 38KM8Mask status register data update on individual key for row 1, column 3	
10KM10Mask status register data update on individual key for row 3, column 39KM9Mask status register data update on individual key for row 2, column 38KM8Mask status register data update on individual key for row 1, column 3	
9 KM9 Mask status register data update on individual key for row 2, column 3 8 KM8 Mask status register data update on individual key for row 1, column 3	
8 KM8 Mask status register data update on individual key for row 1, column 3	
7 KM7 Mask status register data update on individual key for row 4, column 2	
6 KM6 Mask status register data update on individual key for row 3, column 2	
5 KM5 Mask status register data update on individual key for row 2, column 2	
4 KM4 Mask status register data update on individual key for row 1, column 2	
3 KM3 Mask status register data update on individual key for row 4, column 1	
2 KM2 Mask status register data update on individual key for row 3, column 1	
1 KM1 Mask status register data update on individual key for row 2, column 1	
0 KM0 Mask status register data update on individual key for row 1, column 1	

Table 24. Keypad Column Mask Register (Write 0x0051/Read 0x8051)

BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
CM4	CM3	CM2	CM1	0	0	0	0	0	0	0	0	0	0	0	0

Table 25. Keypad Column Mask Register Bit Descriptions (Write 0x0051/Read 0x8051)

BIT	NAME	DESCRIPTION
15	CM4	Mask interrupt, status register, and pending register data update on all keys in column 4
14	CM3	Mask interrupt, status register, and pending register data update on all keys in column 3
13	CM2	Mask interrupt, status register, and pending register data update on all keys in column 2
12	CM1	Mask interrupt, status register, and pending register data update on all keys in column 1
[11:0]	0	Reserved

Table 26. GPIO Control Register (Write 0x004F/Read 0x804F)

						-				-					
BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
GP7	GP6	GP5	GP4	GP3	GP2	GP1	GP0	OE7	OE6	OE5	OE4	OE3	OE2	OE1	OE0

Table 27. GPIO Control Register Bit Descriptions (Write 0x004F/Read 0x804F)

ріт	NAME		DESCRIPTION
BIT	NAME	1	0
15	GP7	C4 pin becomes GPIO pin 7	C4 pin remains keypad column 4
14	GP6	C3 pin becomes GPIO pin 6	C3 pin remains keypad column 3
13	GP5	C2 pin becomes GPIO pin 5	C2 pin remains keypad column 2
12	GP4	C1 pin becomes GPIO pin 4	C1 pin remains keypad column 1
11	GP3	R4 pin becomes GPIO pin 3	R4 pin remains keypad row 4
10	GP2	R3 pin becomes GPIO pin 2	R3 pin remains keypad row 3
9	GP1	R2 pin becomes GPIO pin 1	R2 pin remains keypad row 2
8	GP0	R1 pin becomes GPIO pin 0	R1 pin remains keypad row 1
[7:0]	[OE7:OE0]	GPIO pin configured as an output	GPIO pin configured as an input

Table 28.GPIO Pullup Disable Register (Write 0x004E/Read 0x804E)

BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
PU7	PU6	PU5	PU4	PU3	PU2	PU1	PU0	0	0	0	0	0	0	0	0

Table 29. GPIO Pullup Disable RegisterDescriptions

BIT	NAME	DESCRIPTION
[15:8]	[PU7:PU0]	1: Pullup disabled. Open collector output. 0: Pullup enabled.
[7:0]	0	Reserved: always write as zero.

Data Registers

The data results from conversions or keypad scans are held in the data registers of the MAX1233/MAX1234. During power-up, all of these data registers with the exception of the DAC data register default to $0000_{\rm H}$. The DAC register defaults to $1000_{\rm H}$.

Analog Input Data Registers

Table 30 shows the format of the \dot{X} , Y, Z₁, Z₂, BAT1, BAT2, AUX1, AUX2, TEMP1, and TEMP2 data registers. The data format for these registers is right justified beginning with bit 11. Data written through the serial interface to these registers is not stored.

Keypad Data Registers

Table 31 shows the formatting of the keypad data registers, while Tables 32, 33, and 34 provide individual register bit descriptions. These registers have the same format as the keypad mask register. Each bit represents one key on the keypad. Table 35 shows a map of a 16-key keypad. Data written through the serial interface to these registers is not stored.



READ COMMAND	REGISTER NAME	BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BITO
0x8000	Х	0	0	0	0	X11	X10	Х9	X8	X7	X6	X5	X4	X3	X2	X1	XO
0x8001	Y	0	0	0	0	Y11	Y10	Y9	Y8	Y7	Y6	Y5	Y4	Y3	Y2	Y1	Y0
0x8002	Z1	0	0	0	0	Z1_11	Z1_10	Z1_9	Z1_8	Z1_7	Z1_6	Z1_5	Z1_4	Z1_3	Z1_2	Z1_1	Z1_0
0x8003	Z1	0	0	0	0	Z2_11	Z2_10	Z2_9	Z2_8	Z2_7	Z2_6	Z2_5	Z2_4	Z2_3	Z2_2	Z2_1	Z2_0
0x8005	BATT1	0	0	0	0	B1_11	B1_10	B1_9	B1_8	B1_7	B1_6	B1_5	B1_4	B1_3	B1_2	B1_1	B1_0
0x8006	BATT2	0	0	0	0	B2_11	B2_10	B2_9	B2_8	B2_7	B2_6	B2_5	B2_4	B2_3	B2_2	B2_1	B2_0
0x8007	AUX1	0	0	0	0	A1_11	A1_10	A1_9	A1_8	A1_7	A1_6	A1_5	A1_4	A1_3	A1_2	A1_1	A1_0
0x8008	AUX2	0	0	0	0	A2_11	A2_10	A2_9	A2_8	A2_7	A2_6	A2_5	A2_4	A2_3	A2_2	A2_1	A2_0
0x8009	TEMP1	0	0	0	0	T1_11	T1_10	T1_9	T1_8	T1_7	T1_6	T1_5	T1_4	T1_3	T1_2	T1_1	T1_0
0x800A	TEMP2	0	0	0	0	T2_11	T2_10	T2_9	T2_8	T2_7	T2_6	T2_5	T2_4	T2_3	T2_2	T2_1	T2_0

Table 30. Analog Inputs Data Register Format

Table 31. Keypad Data Registers

READ COMMAND	REGISTER NAME	BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	віто
0x8004	KPD	K15	K14	K13	K12	K11	K10	K9	K8	K7	K6	K5	K4	K3	K2	K1	K0
0x8010	KPData1 (column maskable)	K1_15	K1_14	K1_13	K1_12	K1_11	K1_10	K1_9	K1_8	K1_7	K1_6	K1_5	K1_4	K1_3	K1_2	K1_1	K1_0
0x8011	KPData2 (key maskable)	K2_15	K2_14	K2_13	K2_12	K2_11	K2_10	K2_9	K2_8	K2_7	K2_6	K2_5	K2_4	K2_3	K2_2	K2_1	K2_0

Table 32. Keypad Data Register Descriptions

BIT	NAME	DESCRIPTION
15	K15	Keypad scan result for row 4, column 4. Can only be masked by column mask.
14	K14	Keypad scan result for row 3, column 4. Can only be masked by column mask.
13	K13	Keypad scan result for row 2, column 4. Can only be masked by column mask.
12	K12	Keypad scan result for row 1, column 4. Can only be masked by column mask.
11	K11	Keypad scan result for row 4, column 3. Can only be masked by column mask.
10	K10	Keypad scan result for row 3, column 3. Can only be masked by column mask.
9	K9	Keypad scan result for row 2, column 3. Can only be masked by column mask.
8	K8	Keypad scan result for row 1, column 3. Can only be masked by column mask.
7	K7	Keypad scan result for row 4, column 2. Can only be masked by column mask.
6	K6	Keypad scan result for row 3, column 2. Can only be masked by column mask.
5	K5	Keypad scan result for row 2, column 2. Can only be masked by column mask.
4	K4	Keypad scan result for row 1, column 2. Can only be masked by column mask.
3	K3	Keypad scan result for row 4, column 1. Can only be masked by column mask.
2	K2	Keypad scan result for row 3, column 1. Can only be masked by column mask.
1	K1	Keypad scan result for row 2, column 1. Can only be masked by column mask.
0	K0	Keypad scan result for row 1, column 1. Can only be masked by column mask.

Table 33. Keypad Data Register 1 (Pending Register) Descriptions

BIT	NAME	DESCRIPTION
15	K1_15	Keypad scan result for row 4, column 4. Can only be masked by column mask.
14	K1_14	Keypad scan result for row 3, column 4. Can only be masked by column mask.
13	K1_13	Keypad scan result for row 2, column 4. Can only be masked by column mask.
12	K1_12	Keypad scan result for row 1, column 4. Can only be masked by column mask.
11	K1_11	Keypad scan result for row 4, column 3. Can only be masked by column mask.
10	K1_10	Keypad scan result for row 3, column 3. Can only be masked by column mask.
9	K1_9	Keypad scan result for row 2, column 3. Can only be masked by column mask.
8	K1_8	Keypad scan result for row 1, column 3. Can only be masked by column mask.
7	K1_7	Keypad scan result for row 4, column 2. Can only be masked by column mask.
6	K1_6	Keypad scan result for row 3, column 2. Can only be masked by column mask.
5	K1_5	Keypad scan result for row 2, column 2. Can only be masked by column mask.
4	K1_4	Keypad scan result for row 1, column 2. Can only be masked by column mask.
3	K1_3	Keypad scan result for row 4, column 1. Can only be masked by column mask.
2	K1_2	Keypad scan result for row 3, column 1. Can only be masked by column mask.
1	K1_1	Keypad scan result for row 2, column 1. Can only be masked by column mask.
0	K1_0	Keypad scan result for row 1, column 1. Can only be masked by column mask.

Table 34. Keypad Data Register 2 (Status Register) Descriptions

BIT	NAME	DESCRIPTION
15	K2_15	Keypad scan result for row 4, column 4. Can be masked by key mask or column mask.
14	K2_14	Keypad scan result for row 3, column 4. Can be masked by key mask or column mask.
13	K2_13	Keypad scan result for row 2, column 4. Can be masked by key mask or column mask.
12	K2_12	Keypad scan result for row 1, column 4. Can be masked by key mask or column mask.
11	K2_11	Keypad scan result for row 4, column 3. Can be masked by key mask or column mask.
10	K2_10	Keypad scan result for row 3, column 3. Can be masked by key mask or column mask.
9	K2_9	Keypad scan result for row 2, column 3. Can be masked by key mask or column mask.
8	K2_8	Keypad scan result for row 1, column 3. Can be masked by key mask or column mask.
7	K2_7	Keypad scan result for row 4, column 2. Can be masked by key mask or column mask.
6	K2_6	Keypad scan result for row 3, column 2. Can be masked by key mask or column mask.
5	K2_5	Keypad scan result for row 2, column 2. Can be masked by key mask or column mask.
4	K2_4	Keypad scan result for row 1, column 2. Can be masked by key mask or column mask.
3	K2_3	Keypad scan result for row 4, column 1. Can be masked by key mask or column mask.
2	K2_2	Keypad scan result for row 3, column 1. Can be masked by key mask or column mask.
1	K2_1	Keypad scan result for row 2, column 1. Can be masked by key mask or column mask.
0	K2_0	Keypad scan result for row 1, column 1. Can be masked by key mask or column mask.

DAC Data Register

The DAC data register stores data that is to be written to the 8-bit DAC. Table 36 shows the configuration of the DAC data register. It is right justified with bit 7-bit 0 storing the input data.

GPIO Data Register

Tables 37 and 38 show the format and descriptions for the GPIO data register. The register is left justified with data in bit 15-bit 8. Reading the GPIO data register gives the state of the R_ and C_ pins. Data written to the GPIO data register appears on those R_ and C_ pins, which are configured as general-purpose outputs. Data written to pins not configured as general-purpose outputs is not stored.

ADC Transfer Function

The MAX1233/MAX1234 output data is in straight binary format as shown in Figure 11. This figure shows the ideal output code for the given input voltage and does not include the effects of offset error, gain error, noise, or nonlinearity.

Table 35. Keypad to Key Bit Mapping

COMPONENT	C1	C2	C3	C4
R1	K0	K4	K8	K12
R2	K1	K5	K9	K13
R3	K2	K6	K10	K14
R4	K3	K7	K11	K15

Applications Information Programmable 8-/10-/12-Bit Resolution

The MAX1233/MAX1234 provide the option of three different resolutions for the ADC: 8, 10, or 12 bits. Lower resolutions are practical for some measurements such as touch pressure. Lower resolution conversions have smaller conversion times and therefore consume less power. Program the resolution of the MAX1233/ MAX1234 12-bit ADCs by writing to the RES1 and RES0 bits in the ADC control register. When the MAX1233/ MAX1234 power up, both bits are set to zero so the resolution is set to 8 bits with a 31µs internally timed reference power-up delay as indicated by the ADC resolution control table. As explained in the control register section, the RES1 and RES0 bits control the refer-

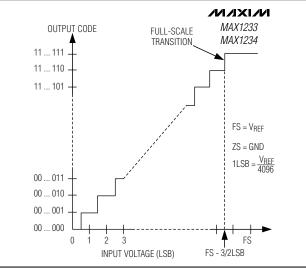


Figure 11. Ideal Input Voltages and Output Codes

Table 36. DAC Data Register(Write 0x000B/Read 0x800B)

BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
0	0	0	0	0	0	0	0	DA7	DA6	DA5	DA4	DA3	DA2	DA1	DA0

Table 37. GPIO Data Register (Write 0x000F/Read 0x800F)

BIT15	BIT14	BIT13	BIT12	BIT11	BIT10	BIT9	BIT8	BIT7	BIT6	BIT5	BIT4	BIT3	BIT2	BIT1	BIT0
GPD7	GPD6	GPD5	GPD4	GPD3	GPD2	GPD1	GPD0	0	0	0	0	0	0	0	0

Table 38. GPIO Data Register Bit Descriptions (Write 0x000F/Read 0x800F)

BIT	NAME	DESCRIPTION
158	GPD70	GPIO data bits for GPIO pins 70
70	0	Reserved

MAX1233/MAX1234

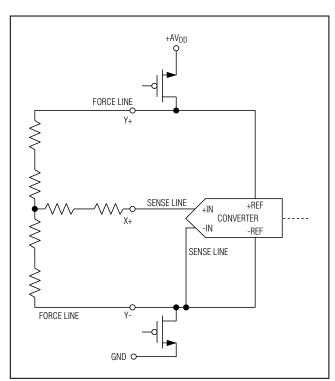


Figure 12. Ratiometric Y-Coordinate Measurement

ence power-up status when the A/D0–A/D3 bits are zero. These values can be set initially on power-up. (Subsequently A/D0–A/D3 bits are not zero, and any other value of these bits is exclusive to ADC resolution programming.)

Differential Ratiometric Touch-Position Measurement

The MAX1233/MAX1234 provide differential conversions. Figure 12 shows the switching matrix configuration for Y coordinate measurement. The +REF and -REF inputs are connected directly to Y+ and Y-. The conversion result is a percentage of the external resistances, and is unaffected by variation in the total touch-screen resistance or the on-resistance of the internal switching matrix. The touch screen remains powered during the acquisition and conversion process.

Touch-Screen Settling

There are two mechanisms that affect the voltage level at the point where the touch panel is pressed. One is electrical ringing due to parasitic capacitance between the top and bottom layers of the touch screen and the other is the mechanical bouncing caused by vibration of the top layer of the touch screen. Thus, the input signal, reference, or both may not settle into their final steady-state values before the ADC samples the inputs, and the reference voltage may continue to change during the conversion cycle. The MAX1233/MAX1234 can be programmed to wait for a fixed amount of time after a screen touch has been detected before beginning a scan. Use the touch-screen settling control bits in the ADC control register (Table 11) to set the settling delay to between zero and 100ms.

The settling problem is amplified in some applications where external filter capacitors may be required across the touch screen to filter noise that may be generated by the LCD panel or backlight circuitry, etc. The values of these capacitors cause an additional settling time requirement when the panel is touched. Any failure to settle before conversion start may show up as a gain error. Average the conversion result by writing to the ADC control register, as shown in Table 10, to minimize noise.

Touch-Pressure Measurement

The MAX1233/MAX1234 provide two methods of measurement of the pressure applied to the touch screen. Although 8-bit resolution is typically sufficient, the following calculations use 12-bit resolution demonstrating the maximum precision of the MAX1233/MAX1234. Figure 13 shows the pressure measurement block diagram.

The first method performs pressure measurements using a known X-plate resistance. After completing three conversions, X-position, Z1-position, and Z2 position, use the following equation to calculate RTOUCH:

$$R_{\text{TOUCH}} = \left(R_{\text{XPLATE}}\right) \times \left(\frac{X_{\text{POSITION}}}{4096}\right) \times \left[\left(\frac{Z_2}{Z_1}\right) - 1\right]$$

The second method requires knowing both the X-plate and Y-plate resistance. Three touch-screen conversions are required in this method as well for measurement of the X-position, Y-position, and Z- position of the touch screen. Use the following equation to calculate RTOUCH:

$$R_{\text{TOUCH}} = \left\{ \left(\frac{R_{\text{XPLATE}}}{Z_1} \right) \times \left(\frac{X_{\text{POSITION}}}{4096} \right) \times \left[\left(\frac{4096}{Z_1} \right) - 1 \right] \right\}$$
$$- \left\{ R_{\text{YPLATE}} \times \left(\frac{Y_{\text{POSITION}}}{4096} \right) \right\}$$

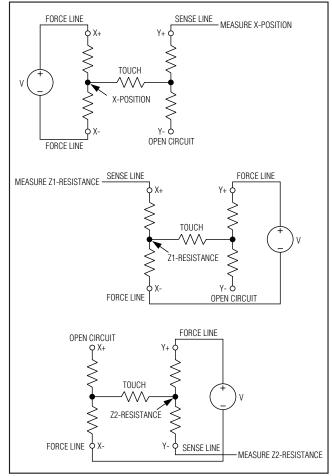


Figure 13. Pressure Measurement Block Diagram

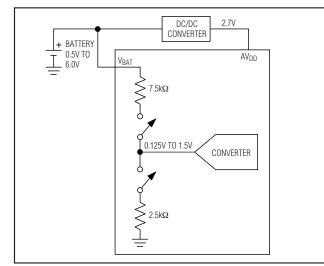


Figure 14. Battery Measurement Block Diagram

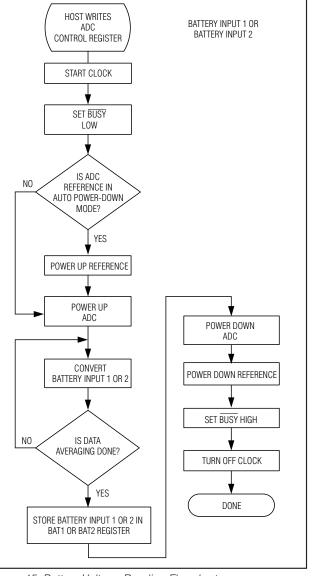


Figure 15. Battery Voltage-Reading Flowchart

Battery-Voltage Monitors

Two dedicated analog inputs (BAT1 and BAT2) allow the MAX1233/MAX1234 to monitor the battery voltages prior to the DC/DC converter. Figure 14 shows the battery voltage monitoring circuitry. The MAX1233/MAX1234 directly monitor battery voltages from 0.5V to 6V. An internal resistor network divides down BAT1 and BAT2 by 4 so that a 6V battery voltage results in a 1.5V input to the ADC. To minimize power consumption, the divider is only enabled during the sampling of BAT1 and BAT2. Figure 15 illustrates the process of battery input reading.

Auxiliary Analog Inputs

Two auxiliary analog inputs (AUX1 and AUX2) allow the MAX1233/MAX1234 to monitor analog input voltages from zero to V_{REF}. Figure 16 illustrates the process of auxiliary input reading.

Temperature Measurements

The MAX1233/MAX1234 provide two temperature measurement options: a single-ended conversion method and a differential conversion method. Both temperature measurement techniques rely on the semiconductor junction's operational characteristics at a fixed current level. The forward diode voltage (V_{BE}) vs. temperature is a well-defined characteristic. The ambient temperature can be predicted in applications by knowing the value of the V_{BE} voltage at a fixed temperature and then monitoring the delta of that voltage as the temperature changes. Figure 17 illustrates the functional block of the internal temperature sensor.

The single conversion method requires calibration at a known temperature, but only requires a single reading to predict the ambient temperature. First, the internal diode forward bias voltage is measured by the ADC at a known temperature. Subsequent diode measurements provide an estimate of the ambient temperature through extrapolation. This assumes a temperature coefficient of -2.1mV/°C. The single conversion method results in a resolution of 0.29°C/LSB (2.5V reference) and 0.12°C/LSB (1.0V reference) with a typical accuracy of $\pm 2^{\circ}$ C. Figure 18 shows the flowchart for the single temperature measurement.

The differential conversion method uses two measurement points. The first measurement is performed with a fixed bias current into the internal diode. The second measurement is performed with a fixed multiple of the original bias current. The voltage difference between the first and second conversion is proportional to the absolute temperature and is expressed by the following formula:

$$\Delta V_{BE} = (kT/q) \times ln(N)$$

where:

 ΔV_{BE} = difference in diode voltage

 $\mathsf{N}=\mathsf{current}$ ratio of the second measurement to the first measurement

k = Boltzmann's constant (1.38 × 10⁻²³ eV/°Kelvin)

q = electron charge $(1.60 \times 10^{-19} \text{ C})$

T = temperature in °Kelvin

The resultant equation solving for °K is:

 $T(^{\circ}K) = q \times \Delta V / (k \times ln(N))$

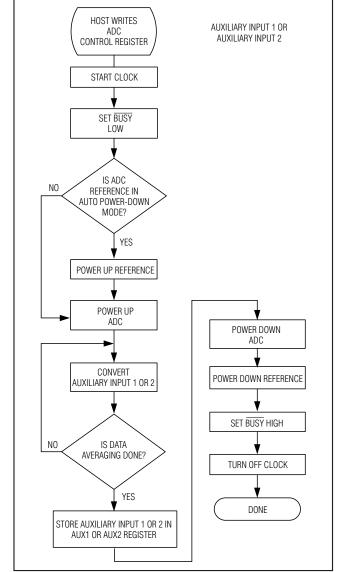


Figure 16. Auxiliary Input Flowchart

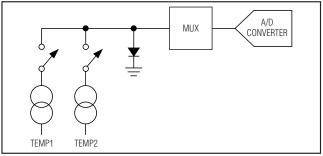


Figure 17. Internal Block Diagram of Temperature Sensor



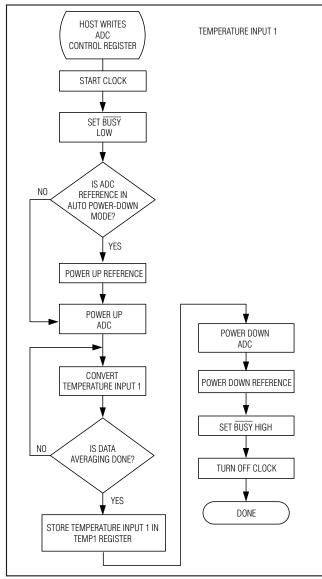


Figure 18. Single Temperature Measurement Process

where:

$$\begin{split} \Delta \mathsf{V} &= \mathsf{V} \; (\mathsf{I} \; \mathsf{N}) - \mathsf{V} \; (\mathsf{I} \mathsf{1}) \; (\text{in mV}) \\ \mathsf{T}(^\circ\mathsf{K}) &= 2.68(^\circ\mathsf{K}/\mathsf{mV}) \times \Delta\mathsf{V}(\mathsf{mV}) \end{split}$$

 $T(^{\circ}C) = [2.68(^{\circ}K/mV) \times \Delta V(mV) - 273^{\circ}K]^{\circ}C/^{\circ}K$

This differential conversion method does not require a test temperature calibration and can provide much improved absolute temperature measurement. In the differential conversion method, however, the resolution

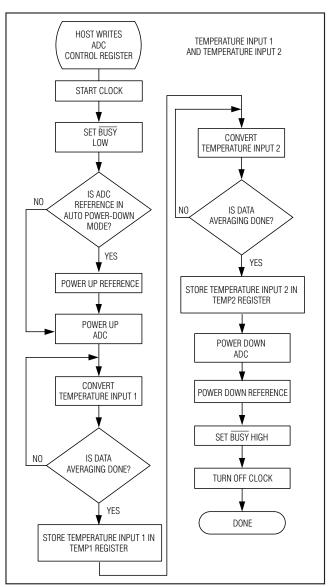


Figure 19. Differential Temperature Measurement Process

is 1.6°C/LSB (2.5V reference) and 0.65°C/LSB (1V reference) with a typical accuracy of \pm 3°C. Figure 19 shows the differential temperature measurement-process.

Note: The bias current for each diode temperature measurement is only turned ON during the acquisition and, therefore, does not noticeably increase power consumption.



Battery Voltage, Auxiliary Input, and Temperature Input Scan

Use this scan to make periodic measurements of both battery inputs, both auxiliary inputs, and both temperature inputs. The respective data registers have the latest results at the end of each cycle. Thus, a single write by the host to the MAX1233/MAX1234 ADC control register results in six different measurements being made. Figure 20 shows this scan operation.

Touch-Initiated Screen Scans (PENSTS = 1; ADSTS = 0)

In the touch-initiated screen-scan mode, the MAX1233/MAX1234 automatically perform a touchscreen scan upon detecting a screen touch. The touchscreen scans performed are determined by the [A/D3:A/D0] written to the ADC control register. Figure 21 shows the flowchart for a complete touch-initiated Xand Y- coordinate scan. Selection of resolution, conversion rate, averaging, and touch-screen settling time determine the overall conversion time.

Figure 22 shows the complete flowchart for a touch-initiated X, Y, and Z scan.

Table 38 shows ADSTS Bit Operation.

Host-Initiated Screen Scans (PENSTS = ADSTS = 0)

In this mode, the host processor decides when a touchscreen scan begins. The MAX1233/MAX1234 detect a screen touch and drive PENIRQ LOW. The host recognizes the interrupt request and can choose to write to the ADC control register to select a touch-screen scan function (PENSTS = ADSTS = 0). Figures 23 and 24 show the process of a host-initiated screen scan.

Key-Press Initiated Debounce Scan (KEYSTS1 = 1, KEYSTS0 =0)

In the key-press initiated debounce mode, the MAX1233/MAX1234 automatically perform a debounce upon detecting a key press. Key scanning begins once a key press has been detected and ends when a key press has been debounced (Figures 25 and 9a).

Host-Initiated Debounce Scan

In this mode, the host processor decides when a debounce scan begins. The MAX1233/MAX1234 detect a key press and drive KEYIRQ low. The host processor recognizes the interrupt request and can choose to write to the keypad control register to initiate a debounce scan (Figures 26 and 9b).

Keypad Debouncing

Keys are debounced either when (1) a key press has been detected, or (2) when commanded by the host MPU.

The keys scanned by the keypad row and column pins are debounced for a period of time (debounce period) as determined by bits [DBN2:DBN0] of the keypad control register.

The keypad controller continues scanning until the keypad stays in the same state for an entire debounce period.

Keypad Data

Keypad data can be read out of either the keypad data status register (maskable), or the keypad data pending register (not maskable). The keypad mask register is used to mask individual keys in the keypad data status register.

GPIO Control

Write to bits [GP7:GP0] of the GPIO control register to configure one or more of the R_C_p ins as a GPIO pin.

Write to bits [OE7:OE0] of the GPIO control register to configure the pins as an input or an output. GPIO data can be read from or written to the GPIO data register. A read returns the logic state of the GPIO pin. A write sets the logic state of a GPIO output pin. Writing to a GPIO input pin has no effect.

GPIO Pullup Disable Register

When programmed as GPIO output, by default, the GPIO pins are active CMOS outputs. Write a 1 to the pullup disable register to configure the GPIO output as an open-drain output.

Using the 8-Bit DAC for LCD/TFT Contrast Control

Design Example:

The 8-bit DAC offers the ability to control biasing of LCD/TFT screens. In the circuit of Figure 27, it is desired to have the MAX1677 DC-DC converter's V_{OUT} to be adjustable.

The minimum and maximum DAC voltages (VDAC(HIGH) and VDAC(LOW)) can be found in the *Electrical Characteristics* table.

The output voltage of the MAX1677 (V_{OUT}) can be calculated by noting the following equations:

$VOUT = VREFDAC + i_1R1$	[Equation 1]
$i_1 = i_2 + i_3$	[Equation 2]
i2 = VREFDAC / R2	[Equation 3]
i3 = (V _{REFDAC} - V _{DAC}) / R3	[Equation 4]

Substituting equations 2, 3, and 4 into equation 1 yields:

VOUT = VREFDAC + (R1 / R2) VREF + (R1 / R3) (VREFDAC - VDAC) [Equation 5]

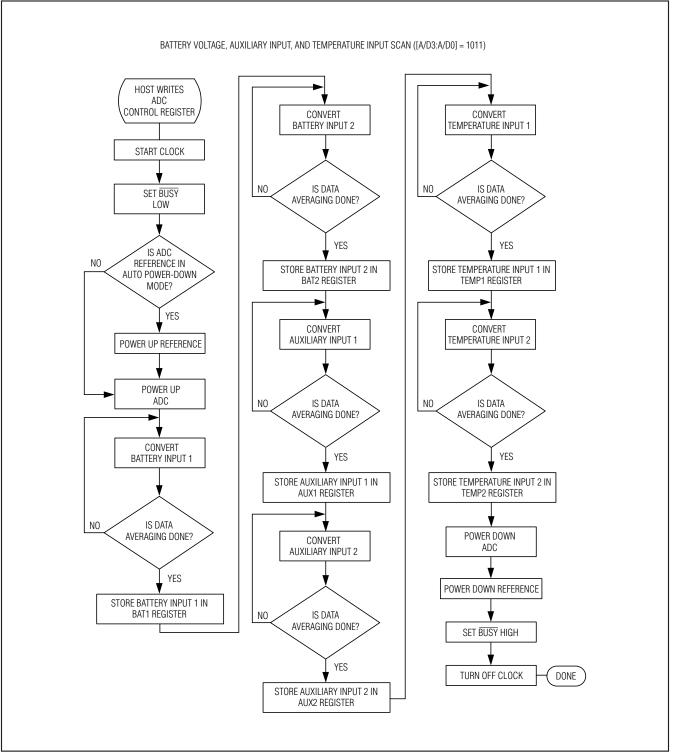


Figure 20. Scan Mode Flowchart

MAX1233/MAX1234

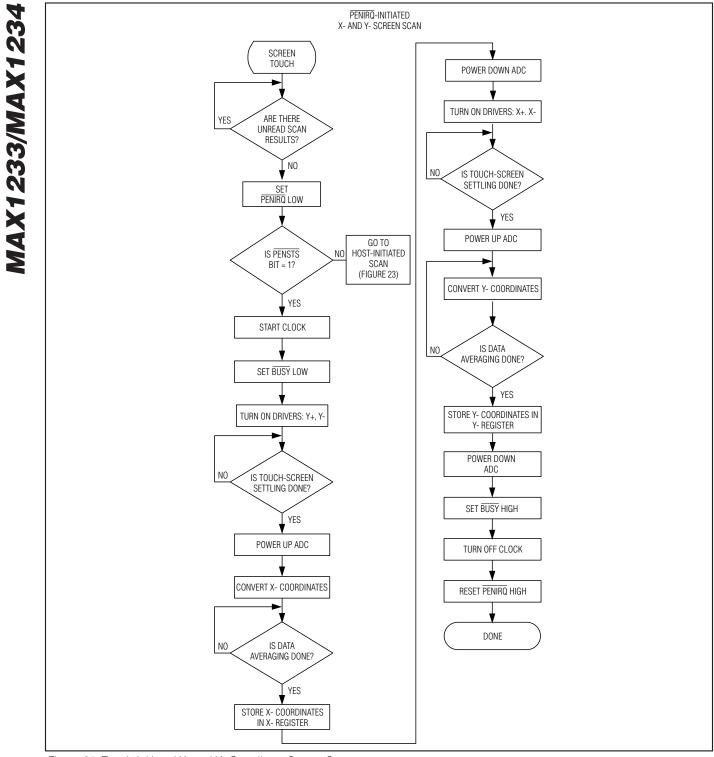


Figure 21. Touch-Initiated X- and Y- Coordinate Screen Scan

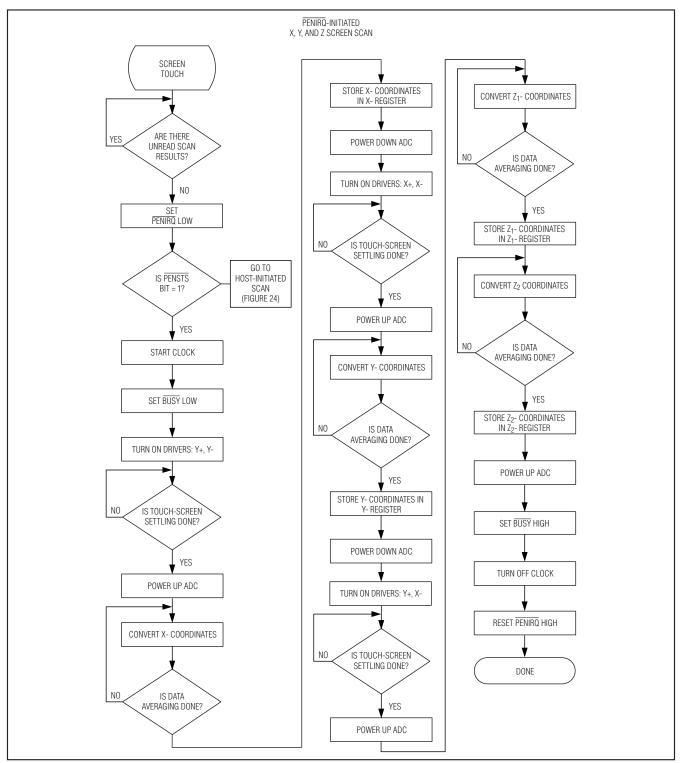


Figure 22. Touch-Initiated X-, Y-, and Z- Coordinate Screen Scan

MAX1233/MAX1234

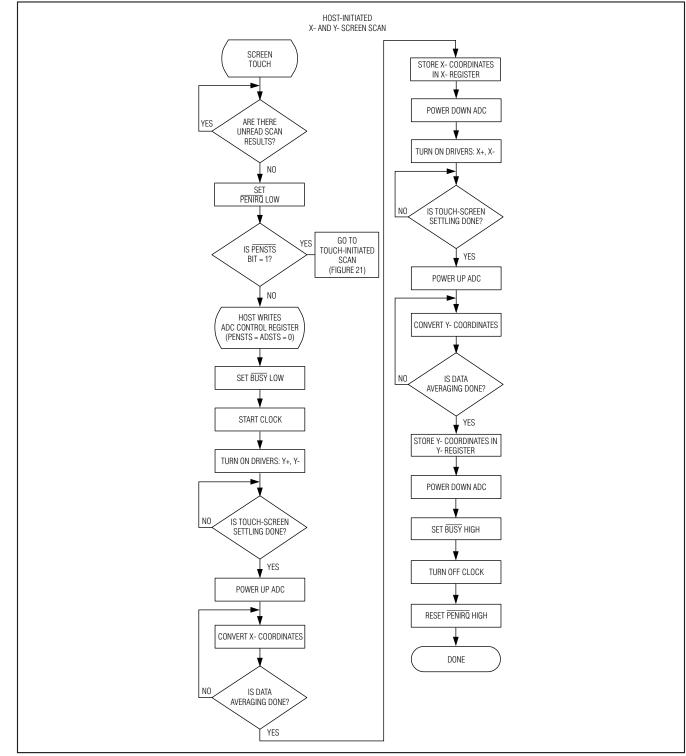


Figure 23. Host-Initiated X- and Y- Coordinate Screen Scan

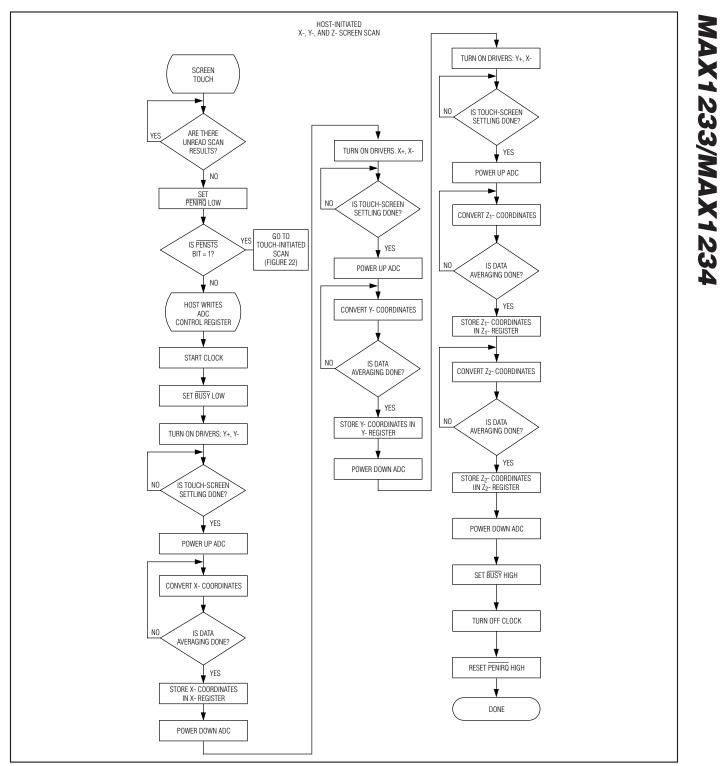
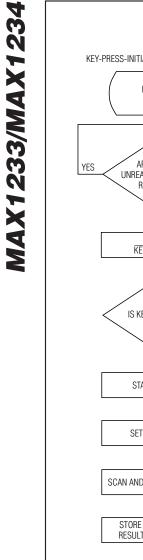
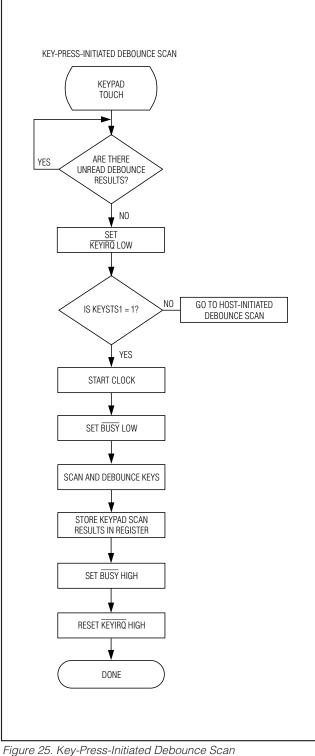


Figure 24. Host-Initiated X-, Y-, and Z- Coordinate Screen Scan





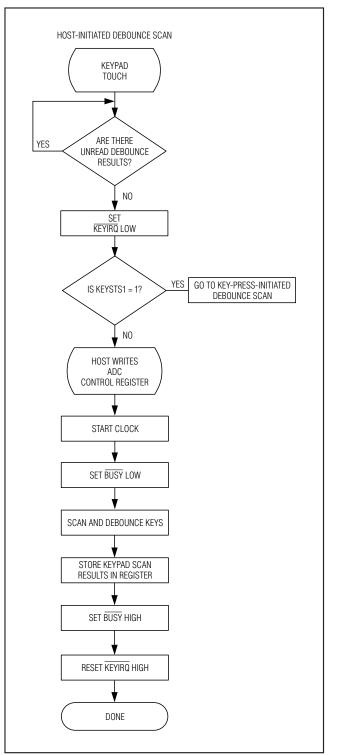


Figure 26. Host-Initiated Debounce Scan

M/IXI/M

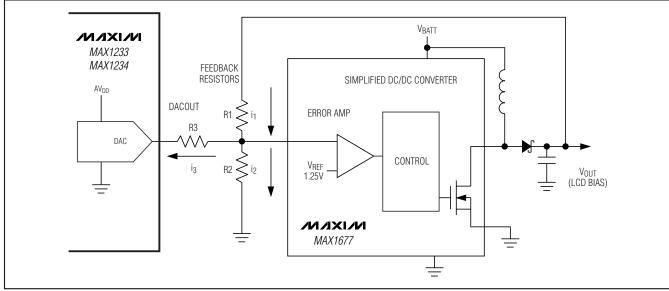


Figure 27. LCD Contrast Control Circuit

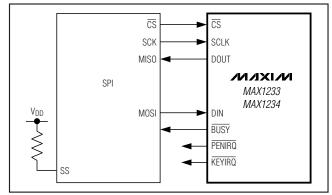


Figure 28a. SPI Interface

Equation 5 shows that the maximum output voltage occurs for the minimum DAC voltage, and that the minimum output voltage occurs for the maximum DAC voltage.

To ensure that the desired output swing is achieved, choose appropriate values of R1, R2, and R3.

Calculate VOUTMAX using the following equation:

Voutmax = Vrefmax + (R1max / R2min)Vrefmax + (R1max / R3min) (Vrefmax - Vdacmin)

[Equation 6]

If VOUTMAX exceeds the maximum ratings of the LCD/TFT display, the DAC codes that cause the output voltage to go too high must be avoided.

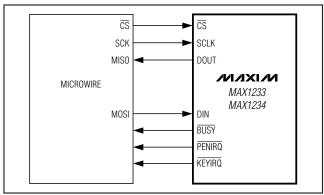


Figure 28b. MICROWIRE Interface

Calculate VOUTMIN using the following equation:

[Equation 7]

If $V_{\mbox{OUTMIN}}$ is too low for desired operation, avoid the DAC codes, which cause the output voltage to go too low.

Connection to Standard Interface SPI and MICROWIRE Interfaces

When using an SPI interface (Figure 28a) or MICROWIRE (Figure 28b), set the CPOL = CPHA = 0. At least four 8-bit operations are necessary to read or write data to/from the MAX1233/MAX1234. DOUT data transitions on the serial clock's falling edge and is clocked into the μ P on the SCLK's rising edge. The first



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MAX1233/MAX1234

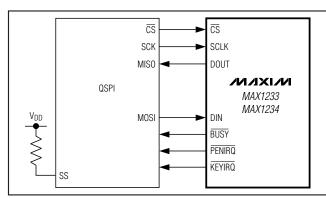


Figure 29. QSPI Interface

MAX1233/MAX1234

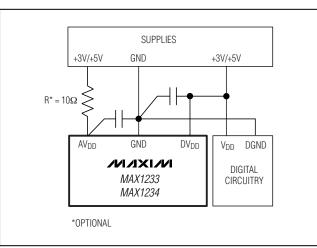


Figure 30. Power-Supply Grounding Connection

two 8-bit data streams write the command word into the MAX1233/MAX1234. The next two 8-bit data streams can contain either the input or output data.

QSPI Interface

Using the high-speed QSPI interface (Figure 29) with CPOL = 0 and CPHA = 0, the MAX1233/MAX1234 support a maximum f_{SCLK} of 10MHz. DOUT data transitions on the serial clock's falling edge and is clocked into the μ P on the SCLK's rising edge.

Layout, Grounding, and Bypassing

For best performance, use printed circuit boards with good layouts; do not use wire-wrap boards even for prototyping. Ensure that digital and analog signal lines are separated from each other. Do not run analog and digital (especially clock) lines parallel to one another, or digital lines underneath the ADC package.

Figure 30 shows the recommended system ground

connections. Establish a single-point analog ground (star ground point) at GND. Connect all analog grounds to the star ground. Connect the digital system ground to the star ground at this point only. For lowest noise operation, the ground return to the star ground's power supply should be low impedance and as short as possible.

High-frequency noise in the power supply may affect the high-speed comparator in the ADC. Bypass the supply to the star ground with a 0.1μ F capacitor as close to pins 1 and 2 of the MAX1233/MAX1234 as possible. Minimize capacitor lead lengths for best supply-noise rejection. If the power supply is very noisy, a 10Ω resistor can be connected as a lowpass filter.

While using the MAX1233/MAX1234 with a resistive touch screen, the interconnection between the converter and the touch screen should be as short and robust as possible. Since resistive touch screens have a low resistance, longer or loose connections are a source of error. Noise can also be a major source of error in touch-screen applications (e.g., applications that require a backlight LCD panel). This EMI noise can be coupled through the LCD panel to the touch screen and cause "flickering" of the converted data. Utilizing a touch screen with a bottom-side metal layer connected to ground couples the majority of noise to ground. In addition, the filter capacitors from Y+, Y-, X+, and Xinputs to ground also help reduce the noise further. Caution should be observed for settling time of the touch screen.

_Definitions

Integral Nonlinearity

Integral nonlinearity (INL) is the deviation of the values on an actual transfer function from a straight line. This straight line can be either a best-straight-line fit or a line drawn between the end points of the transfer function, once offset and gain errors have been nullified. The static linearity parameters for the MAX1233/MAX1234 are measured using the end-point method.

Differential Nonlinearity

Differential nonlinearity (DNL) is the difference between an actual step width and the ideal value of 1LSB. A DNL error specification of less than 1LSB guarantees no missing codes and a monotonic transfer function.

Aperture Jitter

Aperture jitter (t_{AJ}) is the sample-to-sample variation in the time between the samples.

Aperture Delay

Aperture delay (t_{AD}) is the time defined between the falling edge of the sampling clock and the instant when an actual sample is taken.



Signal-to-Noise Ratio

For a waveform perfectly reconstructed from digital samples, signal-to-noise ratio (SNR) is the ratio of full-scale analog input (RMS value) to the RMS quantization error (residual error). The ideal, theoretical minimum analogto-digital noise is caused by quantization error only and results directly from the ADC's resolution (N bits):

In reality, there are other noise sources besides quantization noise: thermal noise, reference noise, clock jitter, etc. SNR is computed by taking the ratio of the RMS signal to the RMS noise, which includes all spectral components minus the fundamental, the first five harmonics, and the DC offset.

Signal-to-Noise Plus Distortion

Signal-to-noise plus distortion (SINAD) is the ratio of the fundamental input frequency's RMS amplitude to the RMS equivalent of all other ADC output signals:

SINAD (dB) = 20 × log (SignalRMS / NoiseRMS)

Effective Number of Bits

Effective number of bits (ENOB) indicates the global accuracy of an ADC at a specific input frequency and sampling rate. An ideal ADC's error consists of quantization noise only. With an input range equal to the full-scale range of the ADC, calculate the effective number of bits as follows:

$$ENOB = (SINAD - 1.76) / 6.02$$

Total Harmonic Distortion

Total harmonic distortion (THD) is the ratio of the RMS sum of the first five harmonics of the input signal to the fundamental itself. This is expressed as:

THD = 20 × log
$$\left(\sqrt{\frac{V_2^2 + V_3^2 + V_4^2 + V_5^2}{V_1^2}}\right)$$

where V_1 is the fundamental amplitude, and V_2 through V_5 are the amplitudes of the 2nd- through 5th-order harmonics, respectively.

Spurious-Free Dynamic Range

Spurious-free dynamic range (SFDR) is the ratio of RMS amplitude of the fundamental (maximum signal component) to the RMS value of the next-largest distortion component.

Chip Information

TRANSISTOR COUNT: 28,629

Package Information

For the latest package outline information, go to **www.maxim-ic.com/packages**.

PACKAGE TYPE	PACKAGE CODE	DOCUMENT NO.		
28 QFN	G2855-2	<u>21-0091</u>		
28 TQFN	T2855-6	<u>21-0140</u>		

Revision History

REVISION NUMBER	REVISION DATE	DESCRIPTION	PAGES CHANGED
0	7/02	Initial release	—
4	3/08	Added register address information. Fixed DCLK typo. Fixed CS timing dependency.	12, 18–27, 29, 41, 42

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